



# VND5E004A-E VND5E004ASP30-E

Double 4mΩ high-side driver with analog current sense  
for automotive applications

## Features

Max transient supply voltage	V <sub>CC</sub>	41 V
Operating voltage range	V <sub>CC</sub>	4.5 to 28 V
Max on-state resistance (per ch.)	R <sub>ON</sub>	4 mΩ
Current limitation (typ)	I <sub>LIMH</sub>	90 A
Off-state supply current	I <sub>S</sub>	2 μA <sup>(1)</sup>

1. Typical value with all loads connected

- General
  - Very low standby current
  - 3.0 V CMOS compatible inputs
  - Optimized electromagnetic emissions
  - Very low electromagnetic susceptibility
  - Compliant with European directive 2002/95/EC
  - Very low current sense leakage
- Diagnostic functions
  - Proportional load current sense
  - High current sense precision for wide currents range
  - Diagnostic enable pin
  - Off-state open-load detection
  - Output short to V<sub>CC</sub> detection
  - Overload and short to ground (power limitation) indication
  - Thermal shutdown indication
- Protection
  - Undervoltage shutdown
  - Overvoltage clamp
  - Load current limitation
  - Self limiting of fast thermal transients
  - Protection against loss of ground and loss of V<sub>CC</sub>
  - Overtemperature shutdown with auto restart (thermal shutdown)
  - Inrush current active management by power limitation



- Reverse battery protection with self switch on of the Power MOSFET
- Electrostatic discharge protection

## Applications

- All types of resistive, inductive and capacitive loads
- Suitable for power management applications

## Description

The VND5E004A-E and VND5E004ASP30-E are double channel high-side drivers manufactured using ST proprietary VIPower™ M0-5 technology and housed in PQFN-12x12 power lead-less and MultiPowerSO-30 packages. The devices are designed to drive 12 V automotive grounded loads, and to provide protection and diagnostics. They also implement a 3 V and 5 V CMOS-compatible interface for use with any microcontroller.

The devices integrate advanced protective functions such as load current limitation, inrush and overload active management by power limitation, overtemperature shut-off with auto-restart and overvoltage active clamp. A dedicated analog current sense pin is associated with every output channel providing enhanced diagnostic functions including fast detection of overload and short-circuit to ground through power limitation indication, overtemperature indication, short-circuit to V<sub>CC</sub> diagnosis and on-state and off-state open-load detection. The current sensing and diagnostic feedback of the whole device can be disabled by pulling the DE pin low to share the external sense resistor with similar devices.

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# 1 Block diagram and pin configurations

Figure 1. Block diagram

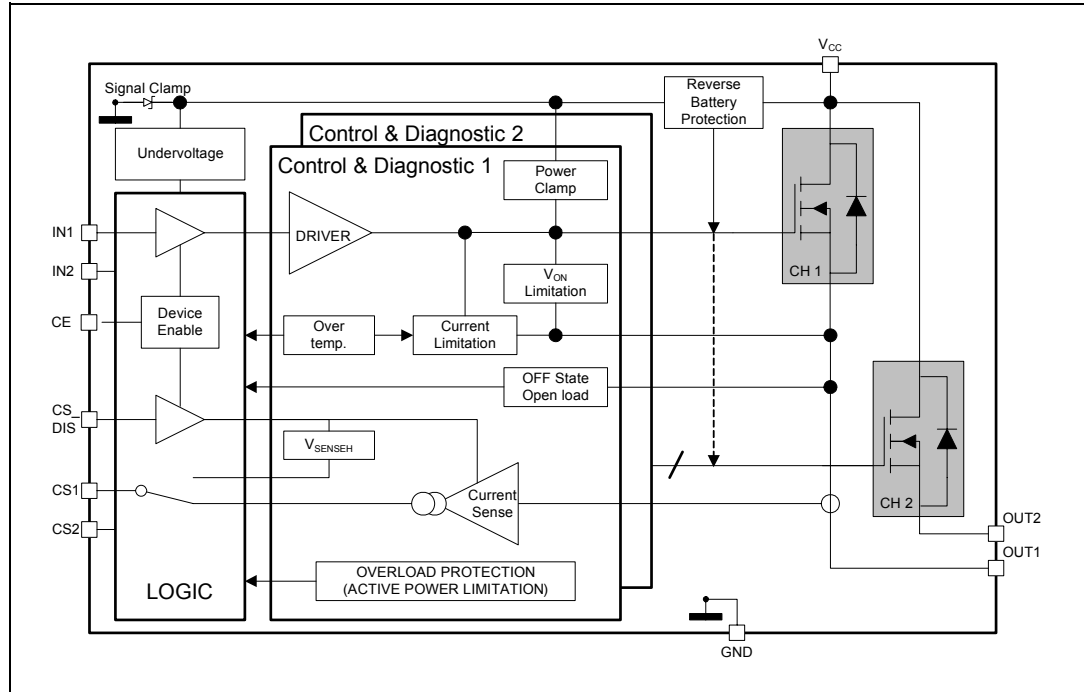


Table 1. Pin functions

Name	Function
V <sub>CC</sub>	Battery connection
OUT1,2	Power output
GND	Ground connection
IN1,2	Voltage controlled input pin with hysteresis, CMOS compatible, controls output switch state
CS1,2	Analog current sense pin; delivers a current proportional to the load current
DE	Active high diagnostic enable pin

Figure 2. Configuration diagram (not in scale)

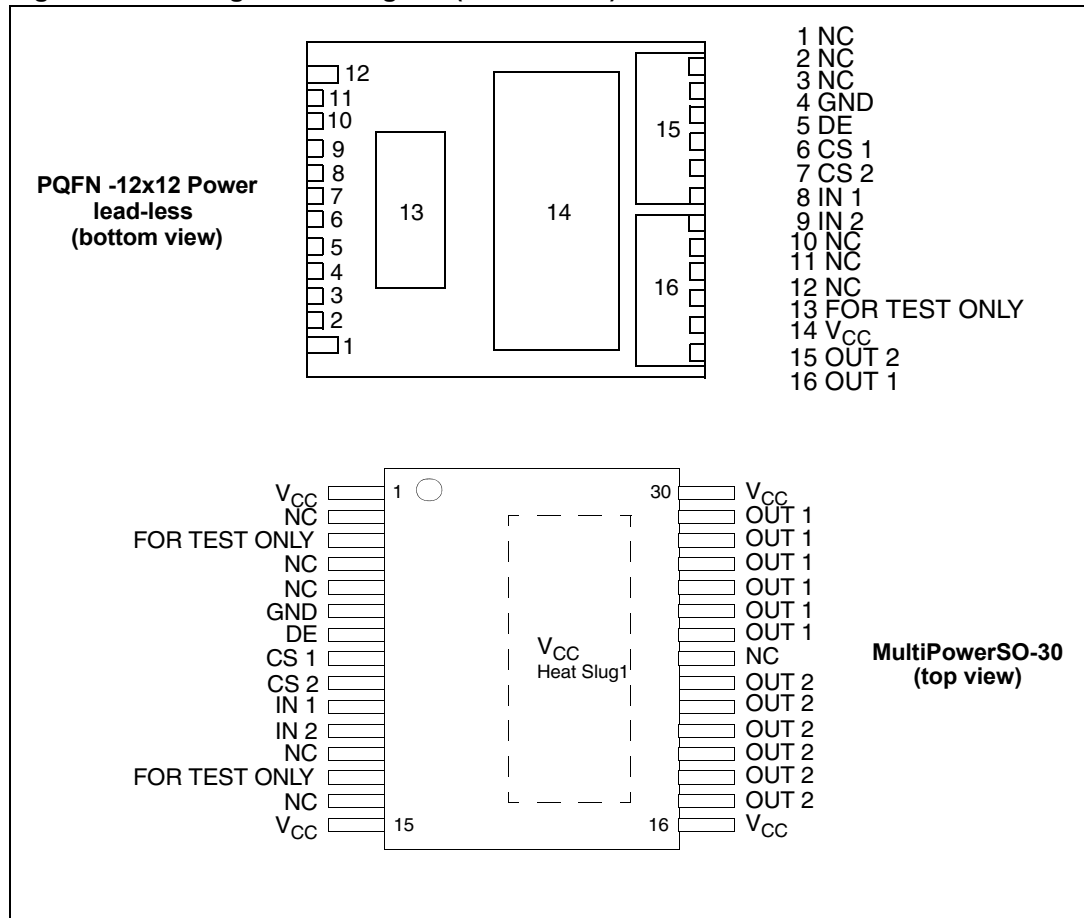


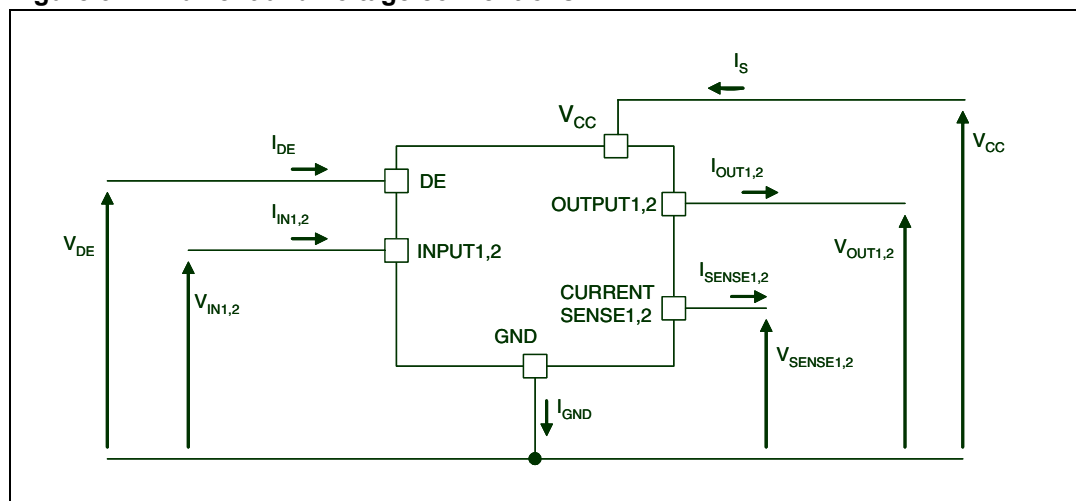
Table 2. Suggested connections for unused and not connected pins

Connection / pin	Current sense	NC <sup>(1)</sup>	Output	Input	DE	For test only
Floating	Not allowed	X	X	X	X	X
To ground	Through 1kΩ resistor	X	Not allowed	Through 10kΩ resistor	Through 10kΩ resistor	Not allowed

1. Not connected

## 2 Electrical specifications

Figure 3. Current and voltage conventions



### 2.1 Absolute maximum ratings

Applying stress which exceeds above the ratings listed in [Table 3: Absolute maximum ratings](#) may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to the conditions in this section for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

Table 3. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC supply voltage	28	V
V <sub>CCPK</sub>	Transient supply voltage (T < 400 ms, R <sub>load</sub> > 0.5 Ω)	41	V
-V <sub>CC</sub>	Reverse DC supply voltage	16	V
I <sub>OUT</sub>	DC output current	Internally limited	A
- I <sub>OUT</sub>	Reverse DC output current	70	A
I <sub>IN</sub>	DC input current	-1 to 10	mA
I <sub>DE</sub>	DC diagnostic enable input current	-1 to 10	mA
V <sub>CSSENSE</sub>	Current sense maximum voltage (V <sub>CC</sub> > 0 V)	V <sub>CC</sub> -41 +V <sub>CC</sub>	V V
E <sub>MAX</sub>	Maximum switching energy (single pulse) (L = 0.3 mH; R <sub>L</sub> = 0 Ω; V <sub>bat</sub> = 13.5 V; T <sub>jstart</sub> = 150 °C; I <sub>OUT</sub> = I <sub>limL</sub> (Typ.))	600	mJ
V <sub>ESD</sub>	Electrostatic discharge (Human Body Model: R = 1.5 kΩ; C = 100 pF)	2000	V

**Table 3. Absolute maximum ratings (continued)**

Symbol	Parameter	Value	Unit
V <sub>ESD</sub>	Charge device model (CDM-AEC-Q100-011)	750	V
T <sub>j</sub>	Junction operating temperature	-40 to 150	°C
T <sub>STG</sub>	Storage temperature	-55 to 150	°C

## 2.2 Thermal data

**Table 4. Thermal data**

Symbol	Parameter	Maximum value		Unit
		MultiPowerSO-30	12x12 PLLP	
R <sub>thj-case</sub>	Thermal resistance junction-case (with one channel ON)	0.35	0.35	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	58 <sup>(1)</sup>	39 <sup>(2)</sup>	°C/W

1. PCB FR4 area 58 mm x 58 mm, PCB thickness 2 mm, Cu thickness 35 μm, minimum pad layout

2. PCB FR4 area 78 mm x 78 mm, PCB thickness 2 mm, Cu thickness 35 μm, minimum pad layout

## 2.3 Electrical characteristics

Values specified in this section are for  $8\text{ V} < V_{CC} < 24\text{ V}$ ,  $-40\text{ °C} < T_j < 150\text{ °C}$ , unless otherwise stated.

**Table 5. Power section**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{CC}$	Operating supply voltage		4.5	13	28	V
$V_{USD}$	Undervoltage shutdown			3.5	4.5	V
$V_{USDhyst}$	Undervoltage shutdown hysteresis			0.5		V
$R_{ON}$	On-state resistance <sup>(1)</sup>	$I_{OUT} = 15\text{ A}$ ; $T_j = 25\text{ °C}$		3		m $\Omega$
		$I_{OUT} = 15\text{ A}$ ; $T_j = 150\text{ °C}$			6	m $\Omega$
		$I_{OUT} = 15\text{ A}$ ; $V_{CC} = 5\text{ V}$ ; $T_j = 25\text{ °C}$			6	m $\Omega$
$R_{ON\ REV}$	$R_{DSon}$ in reverse battery condition	$V_{CC} = -13\text{ V}$ ; $I_{OUT} = -15\text{ A}$ ; $T_j = 25\text{ °C}$		3		m $\Omega$
$V_{clamp}$	$V_{CC}$ clamp voltage	$I_{CC} = 20\text{ mA}$ ; $I_{OUT1,2} = 0\text{ A}$	41	46	52	V
$I_S$	Supply current	Standby $V_{DE} = 0\text{ V}$ ; $V_{CC} = 13\text{ V}$ ; $T_j = 25\text{ °C}$ ; $V_{IN} = 0$ ; $V_{OUT} = V_{SENSE} = 0\text{ V}$		2	5	$\mu\text{A}$
		Off-state; $V_{CC} = 13\text{ V}$ ; $V_{DE} = 5\text{ V}$ ; $T_j = 25\text{ °C}$ ; $V_{IN} = V_{OUT} = V_{SENSE} = 0\text{ V}$		10	15	$\mu\text{A}$
		On-state; $V_{CC} = 13\text{ V}$ ; $V_{DE} = 5\text{ V}$ ; $V_{IN} = 5\text{ V}$ ; $I_{OUT} = 0\text{ A}$		3.5	6	mA
$I_{L(off)}$	Off-state output current <sup>(1)</sup>	$V_{IN} = 0\text{ V}$ or $V_{DE} = 0\text{ V}$ ; $V_{OUT} = 0\text{ V}$ ; $V_{CC} = 13\text{ V}$ ; $T_j = 25\text{ °C}$	0	0.01	3	$\mu\text{A}$
		$V_{IN} = 0\text{ V}$ or $V_{DE} = 0\text{ V}$ ; $V_{OUT} = 0\text{ V}$ ; $V_{CC} = 13\text{ V}$ ; $T_j = 125\text{ °C}$	0		5	$\mu\text{A}$

1. For each channel

**Table 6. Switching ( $V_{CC} = 13\text{ V}$ ;  $T_j = 25\text{ }^\circ\text{C}$ )**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$R_L = 0.87\ \Omega$ (see <a href="#">Table 6</a> )	—	25	—	$\mu\text{s}$
$t_{d(off)}$	Turn-off delay time	$R_L = 0.87\ \Omega$ (see <a href="#">Table 6</a> )	—	35	—	$\mu\text{s}$
$(dV_{OUT}/dt)_{on}$	Turn-on voltage slope	$R_L = 0.87\ \Omega$	—	See <a href="#">Figure 26</a>	—	$\text{V}/\mu\text{s}$
$(dV_{OUT}/dt)_{off}$	Turn-off voltage slope	$R_L = 0.87\ \Omega$	—	See <a href="#">Figure 28</a>	—	$\text{V}/\mu\text{s}$
$W_{ON}$	Switching energy losses during $t_{won}$	$R_L = 0.87\ \Omega$ (see <a href="#">Table 6</a> )	—	5.4	—	mJ
$W_{OFF}$	Switching energy losses during $t_{woff}$	$R_L = 0.87\ \Omega$ (see <a href="#">Table 6</a> )	—	2.3	—	mJ

**Table 7. Logic inputs**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{IL1,2}$	Input low level voltage				0.9	V
$I_{IL1,2}$	Low level input current	$V_{IN} = 0.9\text{ V}$	1			$\mu\text{A}$
$V_{IH1,2}$	Input high level voltage		2.1			V
$I_{IH1,2}$	High level input current	$V_{IN} = 2.1\text{ V}$			10	$\mu\text{A}$
$V_{I(hyst)1,2}$	Input hysteresis voltage		0.25			V
$V_{ICL1,2}$	Input clamp voltage	$I_{IN} = 1\text{ mA}$	5.5		7	V
		$I_{IN} = -1\text{ mA}$		-0.7		V
$V_{DEL}$	DE low level voltage				0.9	V
$I_{DEL}$	DE low level current	$V_{IN} = 0.9\text{ V}$	1			$\mu\text{A}$
$V_{DEH}$	DE high level voltage		2.1			V
$I_{DEH}$	DE high level current	$V_{IN} = 2.1\text{ V}$			10	$\mu\text{A}$
$V_{DE(hyst)}$	DE hysteresis voltage		0.25			V
$V_{DECL}$	DE clamp voltage	$I_{DE} = 1\text{ mA}$	5.5		7	V
		$I_{DE} = -1\text{ mA}$		-0.7		V

**Table 8. Protections and diagnostics (1)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{limH}$	Short circuit current	$V_{CC} = 13\text{ V}$ $5\text{ V} < V_{CC} < 24\text{ V}$	65	90	130 130	A A
$I_{limL}$	Short circuit current during thermal cycling	$V_{CC} = 13\text{ V}; T_R < T_j < T_{TSD}$		40		A
$T_{TSD}$	Shutdown temperature		150	175	200	°C
$T_R$	Reset temperature		$T_{RS}+1$	$T_{RS}+5$		°C
$T_{RS}$	Thermal reset of STATUS		135			°C
$T_{HYST}$	Thermal hysteresis ( $T_{TSD}-T_R$ )			7		°C
$V_{DEMAG}$	Turn-off output voltage clamp	$I_{OUT} = 2\text{ A}; V_{IN} = 0; L = 6\text{ mH}$	$V_{CC}-28$	$V_{CC}-32$	$V_{CC}-35$	V
$V_{ON}$	Output voltage drop limitation	$I_{OUT} = 1\text{ A};$ $T_j = -40\text{ °C to }150\text{ °C}$ (see <a href="#">Figure 8</a> )		25		mV

1. To ensure long term reliability under heavy overload or short circuit conditions, protection and related diagnostic signals must be used together with a proper software strategy. If the device is subjected to abnormal conditions, this software must limit the duration and number of activation cycles.

**Table 9. Current sense (8 V < V<sub>CC</sub> < 18 V)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$K_0$	$I_{OUT}/I_{SENSE}$	$I_{OUT} = 5\text{ A}; V_{SENSE} = 4\text{ V}; V_{DE} = 5\text{ V};$ $T_j = -40\text{ °C...}150\text{ °C}$ $T_j = 25\text{ °C...}150\text{ °C}$	11420 12130	17580 17580	23740 23030	—
$K_1$	$I_{OUT}/I_{SENSE}$	$I_{OUT} = 10\text{ A}; V_{SENSE} = 4\text{ V}; V_{DE} = 5\text{ V};$ $T_j = -40\text{ °C...}150\text{ °C}$ $T_j = 25\text{ °C...}150\text{ °C}$	11830 12680	16910 16910	21990 21140	—
$dK_1/K_1^{(1)}$	Current sense ratio drift	$I_{OUT} = 10\text{ A}; V_{SENSE} = 4\text{ V};$ $V_{DE} = 5\text{ V};$ $T_j = -40\text{ °C to }150\text{ °C}$	-14		+14	%
$K_2$	$I_{OUT}/I_{SENSE}$	$I_{OUT} = 15\text{ A}; V_{SENSE} = 4\text{ V}; V_{DE} = 5\text{ V};$ $T_j = -40\text{ °C...}150\text{ °C}$ $T_j = 25\text{ °C...}150\text{ °C}$	11760 13040	16110 16110	20460 19180	—
$dK_2/K_2^{(1)}$	Current sense ratio drift	$I_{OUT} = 15\text{ A}; V_{SENSE} = 4\text{ V}; V_{DE} = 5\text{ V};$ $T_j = -40\text{ °C to }150\text{ °C}$	-10		+10	%

Table 9. Current sense (8 V < V<sub>CC</sub> < 18 V) (continued)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
K <sub>3</sub>	I <sub>OUT</sub> /I <sub>SENSE</sub>	I <sub>OUT</sub> = 30 A; V <sub>SENSE</sub> = 4 V; V <sub>DE</sub> = 5 V; T <sub>j</sub> = -40 °C...150 °C T <sub>j</sub> = 25 °C...150 °C	13040 13810	15520 15520	18000 17230	—
dK <sub>3</sub> /K <sub>3</sub> <sup>(1)</sup>	Current sense ratio drift	I <sub>OUT</sub> = 30 A; V <sub>SENSE</sub> = 4 V; V <sub>DE</sub> = 5 V; T <sub>j</sub> = -40 °C to 150 °C	-5		+5	%
I <sub>SENSE0</sub>	Analog sense leakage current	I <sub>OUT</sub> = 0 A; V <sub>SENSE</sub> = 0 V; V <sub>DE</sub> = 0 V; V <sub>IN</sub> = 0 V; T <sub>j</sub> = -40 °C...150 °C	0		1	μA
		I <sub>OUT</sub> = 0 A; V <sub>SENSE</sub> = 0 V; V <sub>DE</sub> = 5 V; V <sub>IN</sub> = 5 V; T <sub>j</sub> = -40 °C...150 °C	0		2	μA
		I <sub>OUT</sub> = 15 A; V <sub>SENSE</sub> = 0 V; V <sub>DE</sub> = 0 V; V <sub>IN</sub> = 5 V;	0		1	μA
I <sub>OL</sub>	Open-load on-state current detection threshold	V <sub>IN</sub> = 5 V; 8 V < V <sub>CC</sub> < 18 V I <sub>SENSE</sub> = 5 μA	10		150	mA
V <sub>SENSE</sub>	Max analog sense output voltage	I <sub>OUT</sub> = 45 A; V <sub>CSD</sub> = 0 V; R <sub>SENSE</sub> = 3.9 kΩ	5			V
V <sub>SENSEH</sub>	Analog sense output voltage in fault condition <sup>(2)</sup>	V <sub>CC</sub> = 13 V; R <sub>SENSE</sub> = 3.9 kΩ		8		V
I <sub>SENSEH</sub>	Analog sense output current in fault condition <sup>(2)</sup>	V <sub>CC</sub> = 13 V; V <sub>SENSE</sub> = 5 V		9		mA
t <sub>DSENSE1H</sub>	Delay response time from rising edge of DE pin	V <sub>SENSE</sub> < 4 V, 5 A < I <sub>out</sub> < 30 A I <sub>SENSE</sub> = 90 % of I <sub>SENSE max</sub> (see <a href="#">Figure 4</a> )		50	100	μs
t <sub>DSENSE1L</sub>	Delay response time from falling edge of DE pin	V <sub>SENSE</sub> < 4 V, 5 A < I <sub>out</sub> < 30 A I <sub>SENSE</sub> = 10 % of I <sub>SENSE max</sub> (see <a href="#">Figure 4</a> )		5	20	μs
t <sub>DSENSE2H</sub>	Delay response time from rising edge of INPUT pin	V <sub>SENSE</sub> < 4 V, 5 A < I <sub>out</sub> < 30 A I <sub>SENSE</sub> = 90 % of I <sub>SENSE max</sub> V <sub>DE</sub> = 5 V (see <a href="#">Figure 4</a> )		200	600	μs
t <sub>DSENSE2L</sub>	Delay response time from falling edge of INPUT pin	V <sub>SENSE</sub> < 4 V, 5 A < I <sub>out</sub> < 30 A I <sub>SENSE</sub> = 10 % of I <sub>SENSE max</sub> V <sub>DE</sub> = 5 V (see <a href="#">Figure 4</a> )		100	250	μs

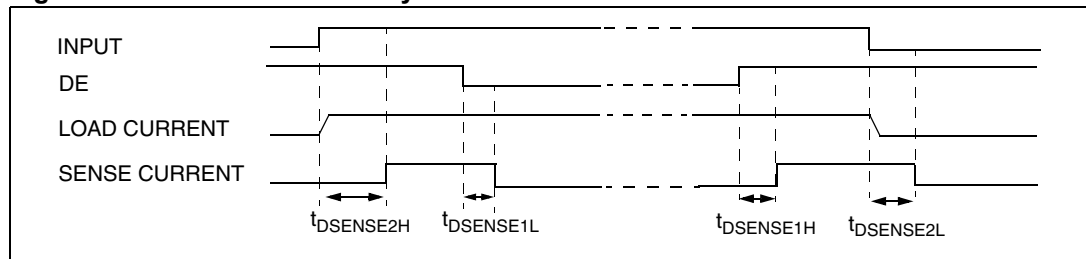
1. Parameter guaranteed by design; it is not tested.

2. Fault condition includes: power limitation, overtemperature and open-load off-state detection.

**Table 10. Open-load detection ( $8V < V_{CC} < 18V$ ,  $V_{DE} = 5V$ )**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{OL}$	Open-load off-state voltage detection threshold	$V_{IN} = 0V$ , $V_{DE} = 5V$ ; See <a href="#">Figure 5</a>	2	—	4	V
$t_{DSTKON}$	Output short circuit to $V_{CC}$ detection delay at turn off	$V_{DE} = 5V$ ; See <a href="#">Figure 5</a>	180	—	1200	$\mu s$
$I_{L(off2)r}$	Off-state output current at $V_{OUT} = 4V$	$V_{IN} = 0V$ ; $V_{SENSE} = 0V$ ; $V_{DE} = 5V$ ; $V_{OUT}$ rising from 0V to 4V	-120	—	90	$\mu A$
$I_{L(off2)f}$	Off-state output current at $V_{OUT} = 2V$	$V_{IN} = 0V$ ; $V_{SENSE} = V_{SENSEH}$ $V_{DE} = 5V$ ; $V_{OUT}$ falling from $V_{CC}$ to 2V	-50	—	90	$\mu A$
$td\_vol$	Delay response from output rising edge to $V_{SENSE}$ rising edge in open-load	$V_{OUT} = 4V$ ; $V_{IN} = 0V$ ; $V_{DE} = 5V$ ; $V_{SENSE} = 90\%$ of $V_{SENSEH}$		—	20	$\mu s$
$td\_voh$	Delay response from output falling edge to $V_{SENSE}$ falling edge in open-load	$V_{OUT} = 2V$ ; $V_{IN} = 0V$ ; $V_{DE} = 5V$ ; $V_{SENSE} = 10\%$ of $V_{SENSEH}$		—	20	$\mu s$

**Figure 4. Current sense delay characteristics**



**Figure 5. Open-load off-state delay timing**

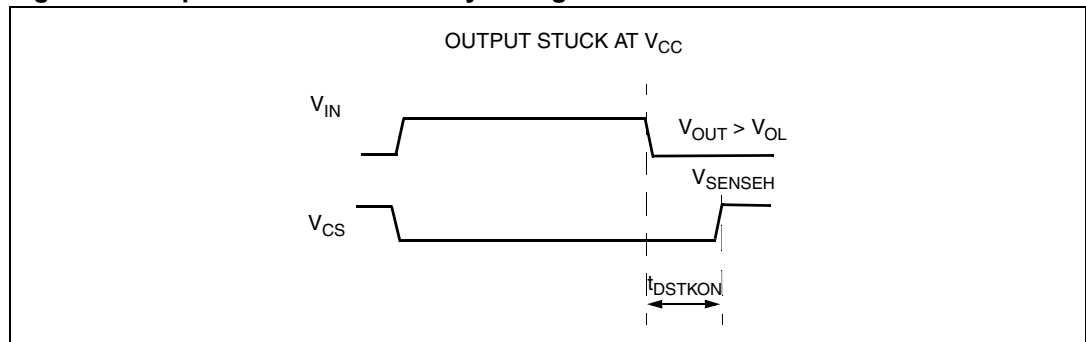


Figure 6. Switching characteristics

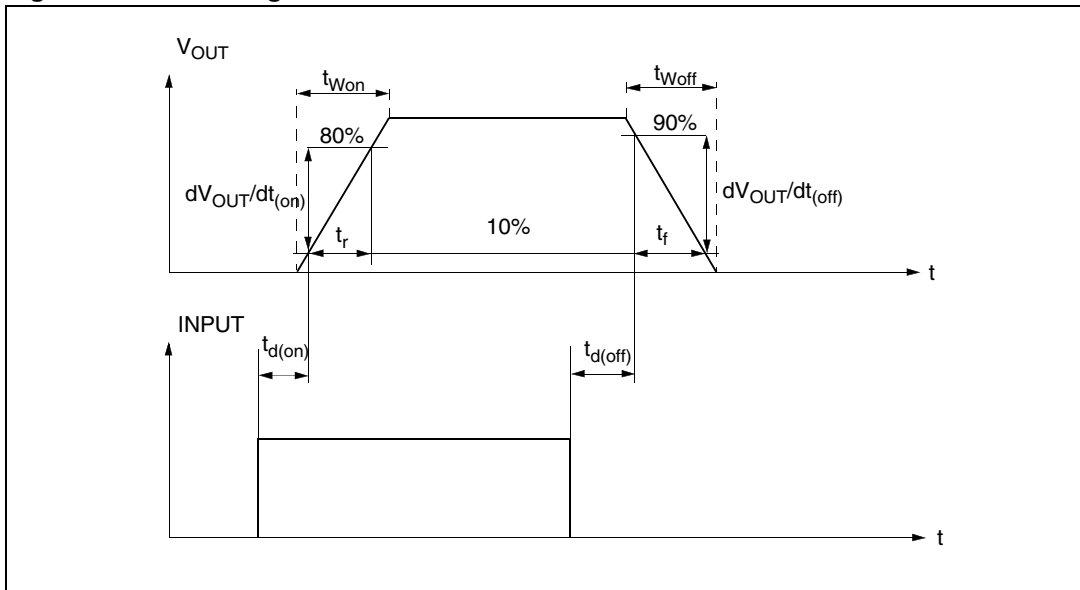


Figure 7. Delay response time between rising edge of output current and rising edge of current sense (CS enabled)

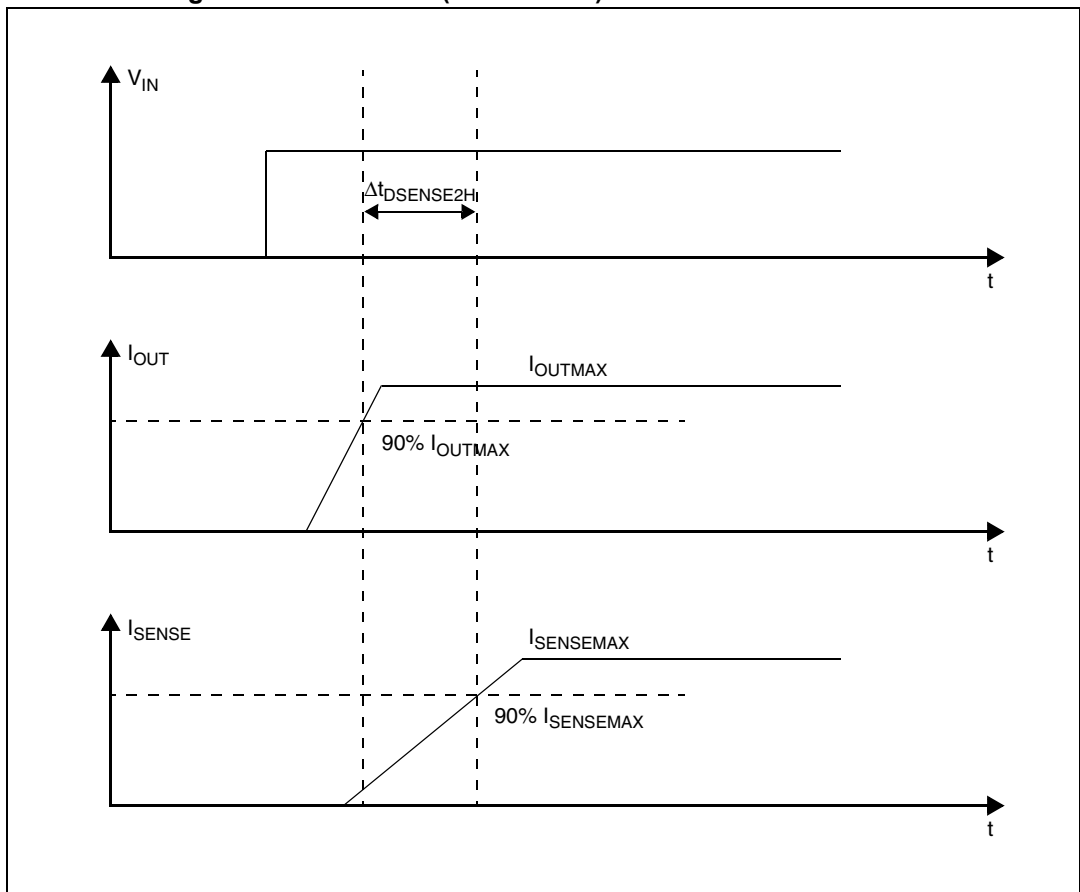


Figure 8. Output voltage drop limitation

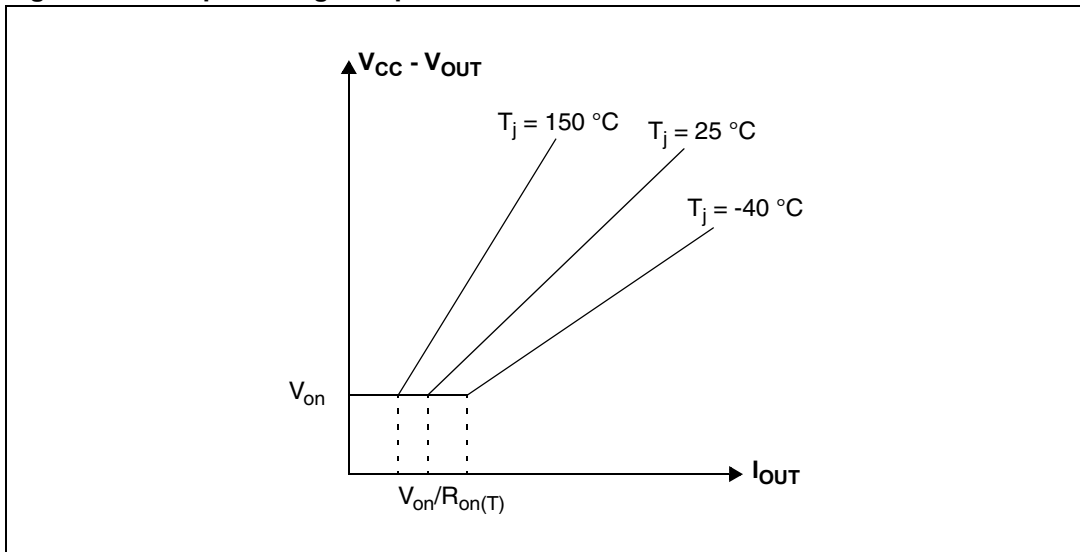


Figure 9.  $I_{OUT}/I_{SENSE}$  vs  $I_{OUT}$

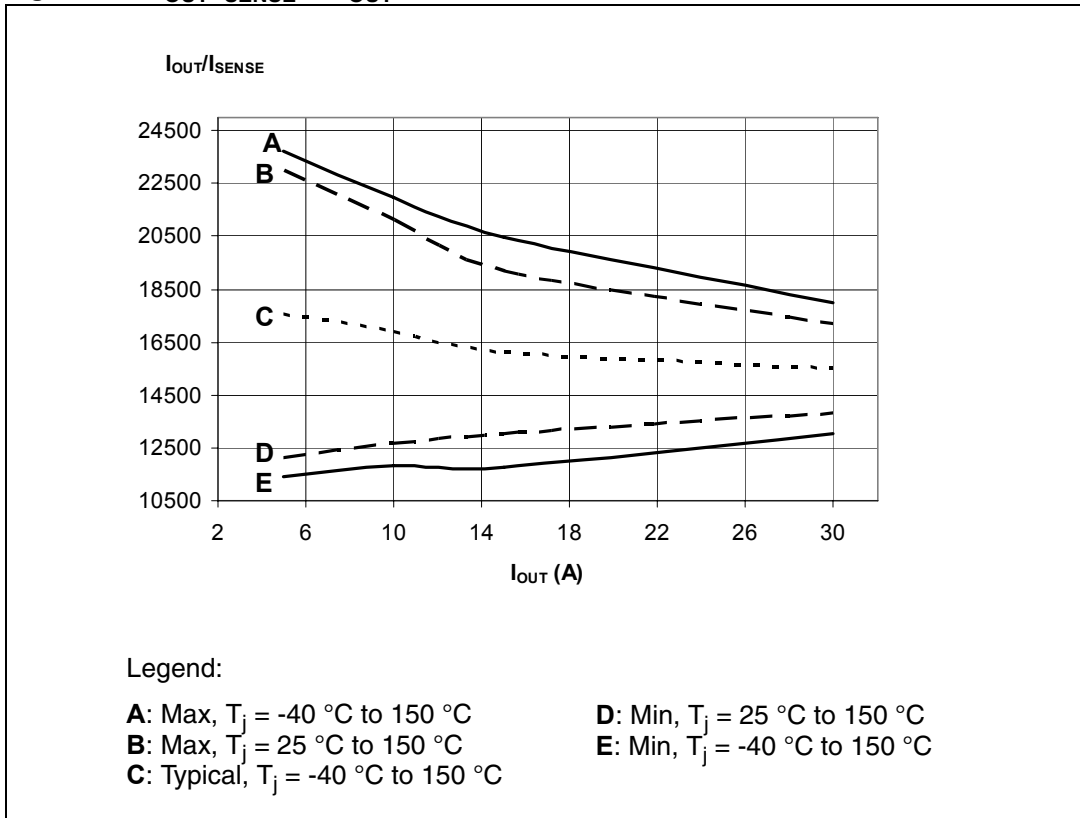
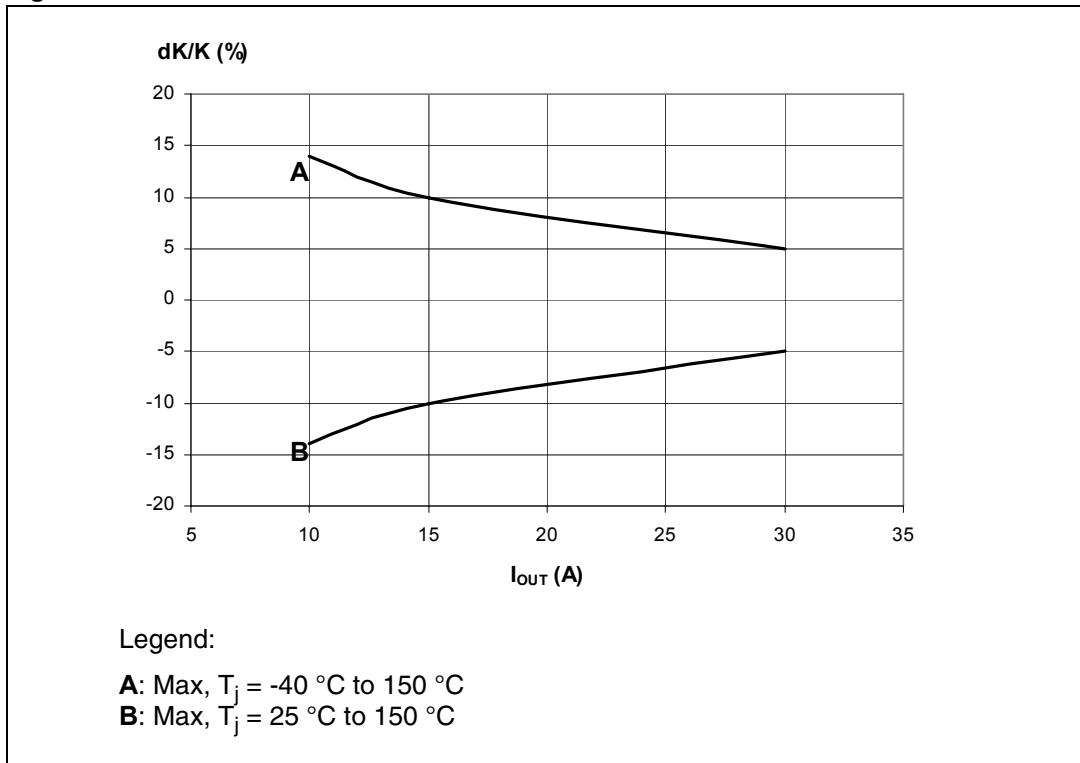


Figure 10. Maximum current sense ratio drift vs load current<sup>(1)</sup>



1. Parameter guaranteed by design; it is not tested.

Table 11. Truth table

Conditions	Enable	Input	Output	Sense (V <sub>DE</sub> =5V) <sup>(1)</sup>
Normal operation	H	L	L	0
	H	H	H	Nominal
Overtemperature	H	L	L	0
	H	H	L	V <sub>SENSEH</sub>
Undervoltage	H	L	L	0
	H	H	L	0
Overload	H	H	X (no power limitation)	Nominal
	H	H	Cycling (power limitation)	V <sub>SENSEH</sub>
Short circuit to GND (Power limitation)	H	L	L	0
	H	H	L	V <sub>SENSEH</sub>
Open-load off-state (with external pull up)	H	L	H	V <sub>SENSEH</sub>
Short circuit to V <sub>CC</sub> (external pull up disconnected)	H	L	H	V <sub>SENSEH</sub>
	H	H	H	< Nominal
Negative output voltage clamp	H	L	L	0

1. If the V<sub>DE</sub> is low, the SENSE output is at a high impedance; its potential depends on leakage currents and external circuit.

**Table 12. Electrical transient requirements (part 1/3)**

ISO 7637-2: 2004(E) Test pulse	Test levels <sup>(1)</sup>		Number of pulses or test times	Burst cycle/pulse repetition time		Delays and impedance
	III	IV				
1	-75 V	-100 V	5000 pulses	0.5 s	5 s	2 ms, 10 Ω
2a	+37 V	+50 V	5000 pulses	0.2 s	5 s	50 μs, 2 Ω
3a	-100 V	-150 V	1h	90 ms	100 ms	0.1 μs, 50 Ω
3b	+75 V	+100 V	1h	90 ms	100 ms	0.1 μs, 50 Ω
4	-6 V	-7 V	1 pulse			100 ms, 0.01 Ω
5b <sup>(2)</sup>	+65 V	+87 V	1 pulse			400 ms, 2 Ω

**Table 13. Electrical transient requirements (part 2/3)**

ISO 7637-2: 2004(E) Test pulse	Test level results <sup>(1)</sup>	
	III	IV
1	C	C
2a	C	C
3a	C	C
3b	C	C
4	C	C
5b <sup>(2)</sup> (3)	C	C

1. The above test levels must be considered referred to Vcc = 13.5V except for pulse 5b
2. Valid in case of external load dump clamp: 40V maximum referred to ground.
3. Suppressed load dump (pulse 5b) is withstood with a minimum load connected as specified in [Table 3](#).

**Table 14. Electrical transient requirements (part 3/3)**

Class	Contents
C	All functions of the device are performed as designed after exposure to disturbance.
E	One or more functions of the device are not performed as designed after exposure to disturbance and cannot be returned to proper operation without replacing the device.

## 2.4 Waveforms

Figure 11. Normal operation

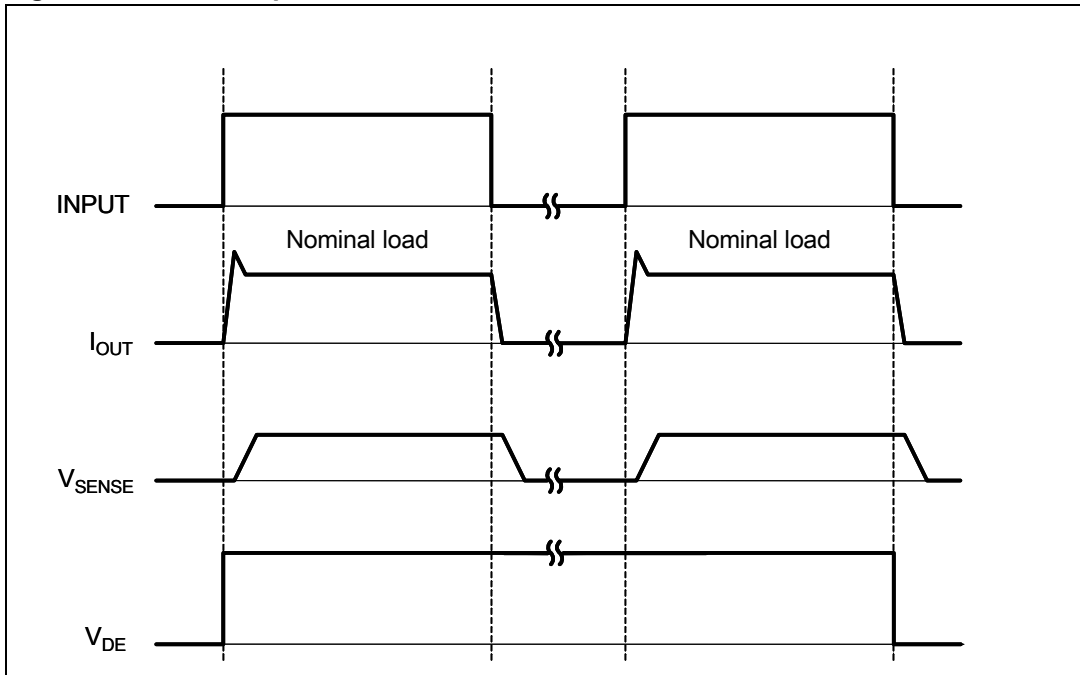


Figure 12. Overload or short to GND

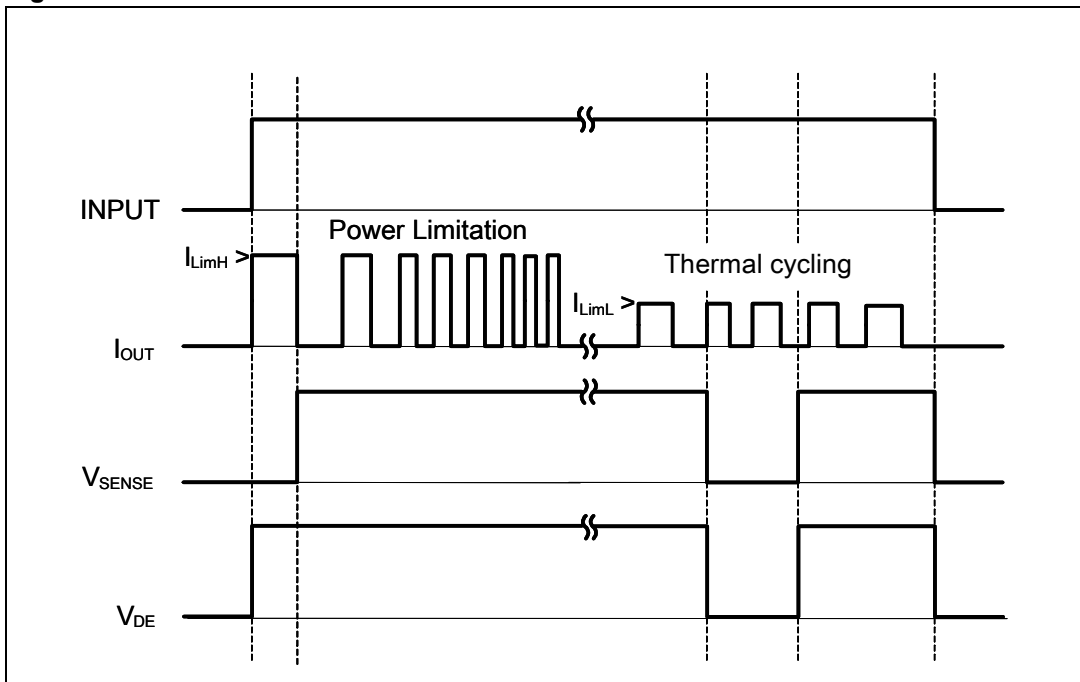


Figure 13. Intermittent overload

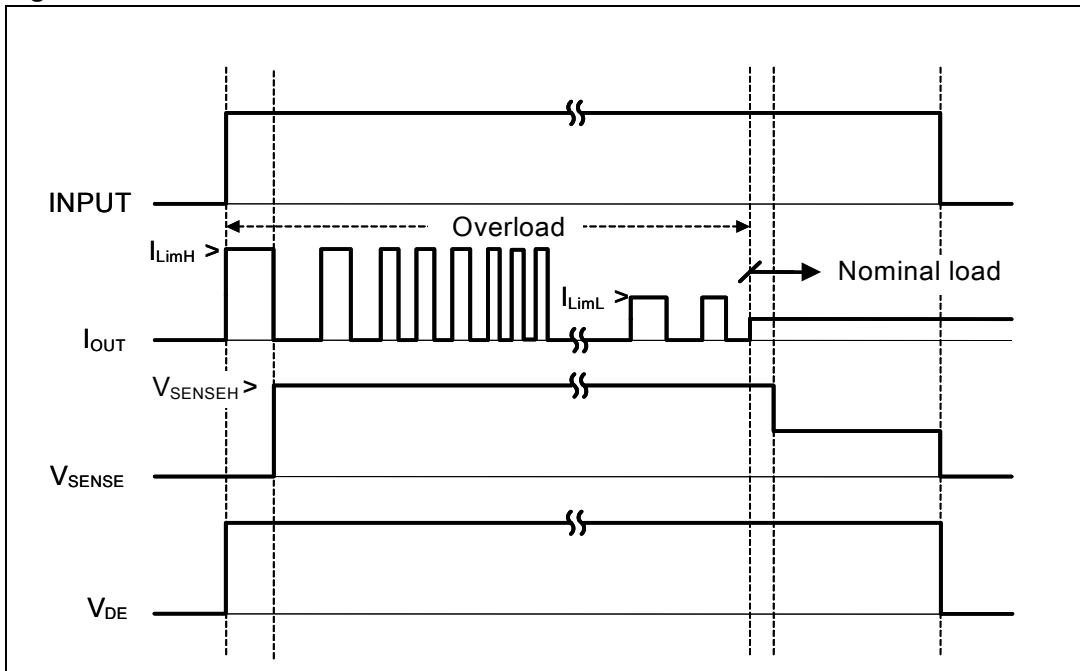


Figure 14. Off-state open-load with external circuitry

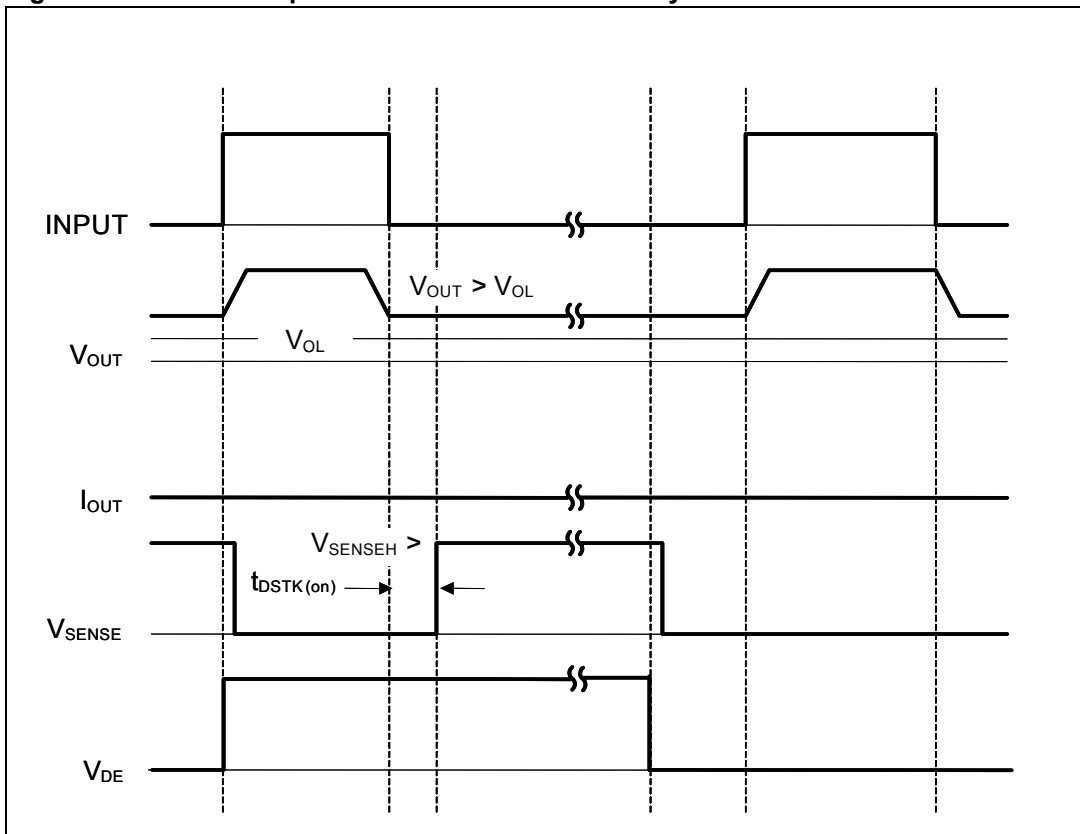


Figure 15. Short to  $V_{CC}$

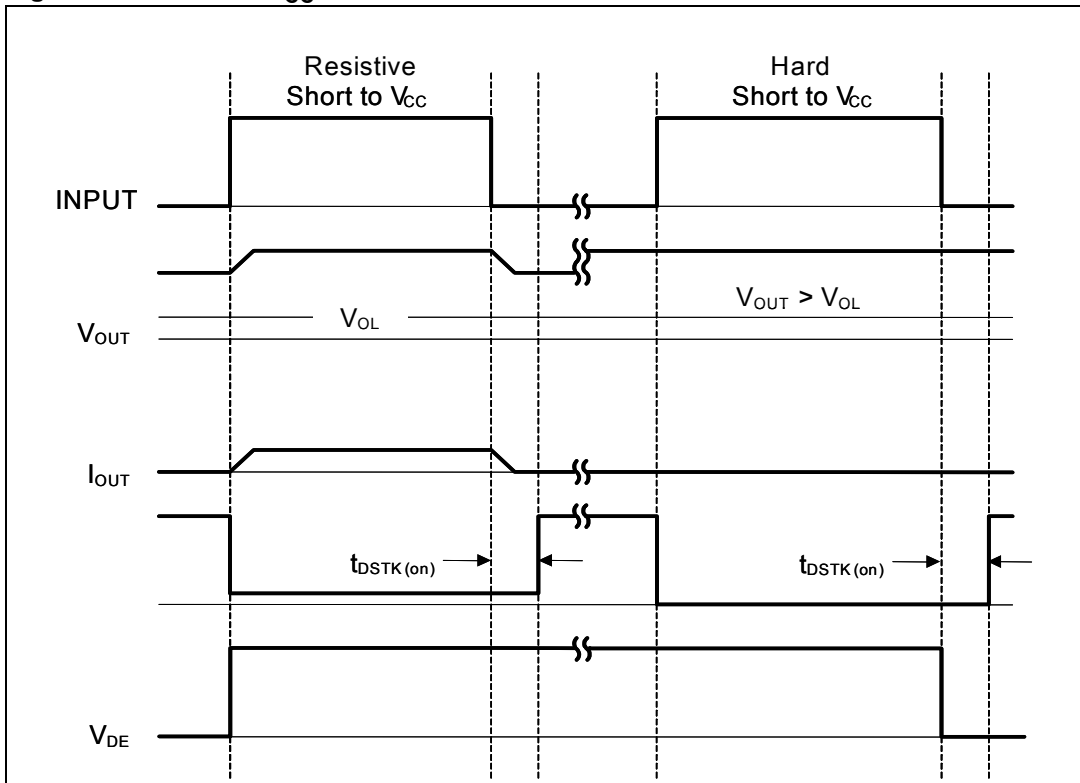
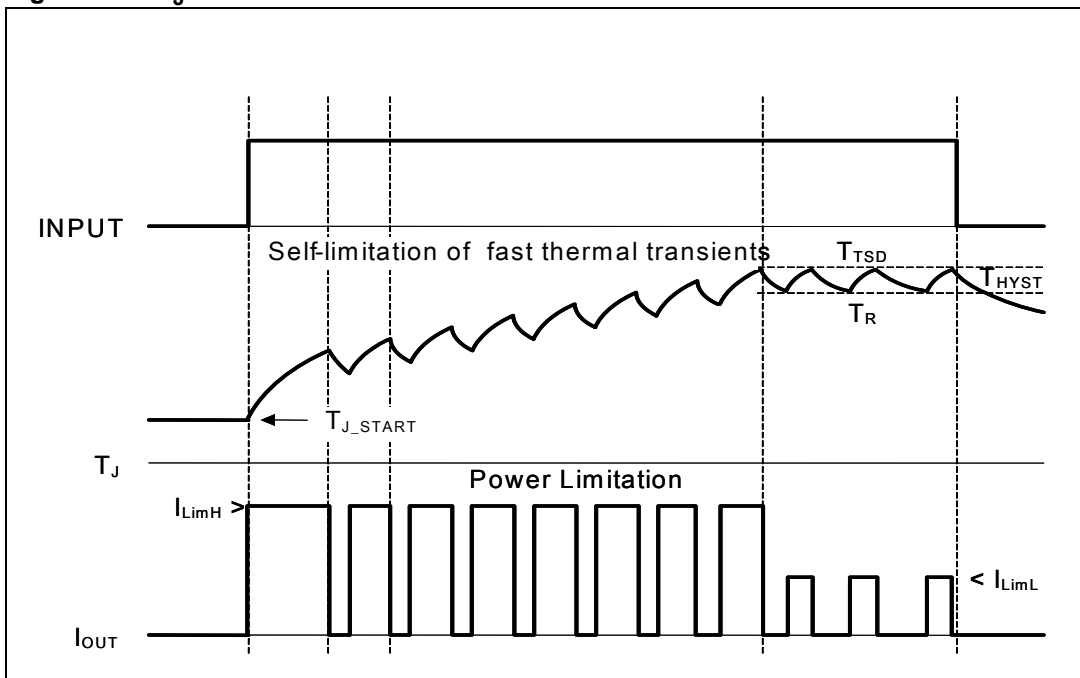


Figure 16.  $T_J$  evolution in overload or short to GND



## 2.5 Electrical characteristics curves

Figure 17. Off-state output current

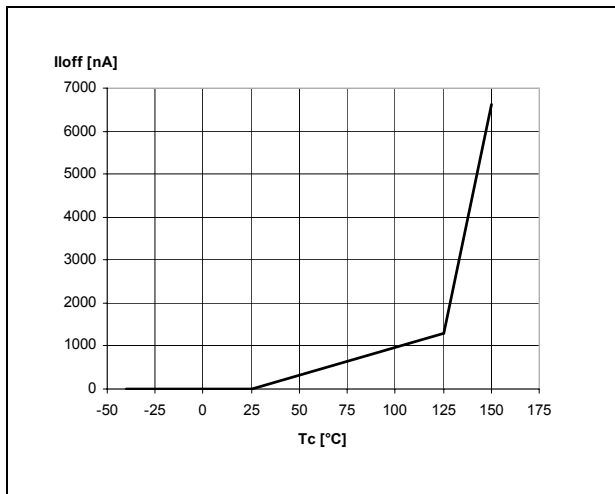


Figure 18. High level input current

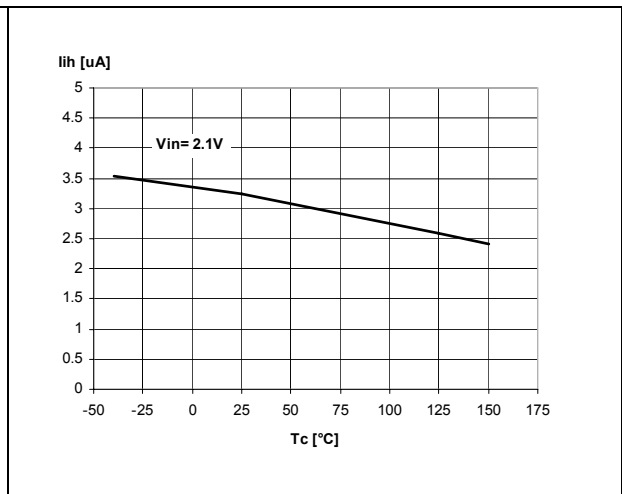


Figure 19. Input clamp voltage

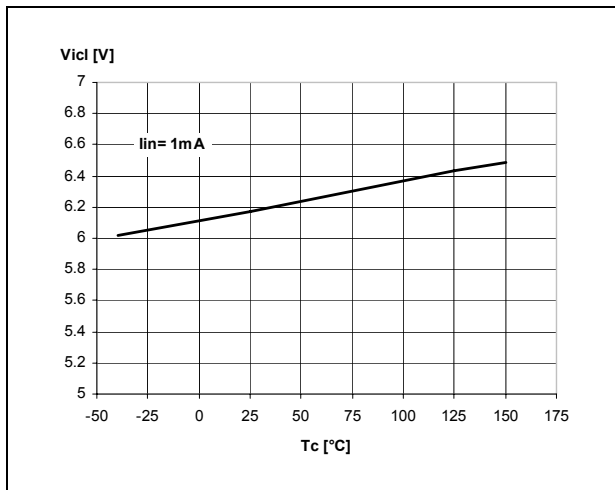


Figure 20. Input low level voltage

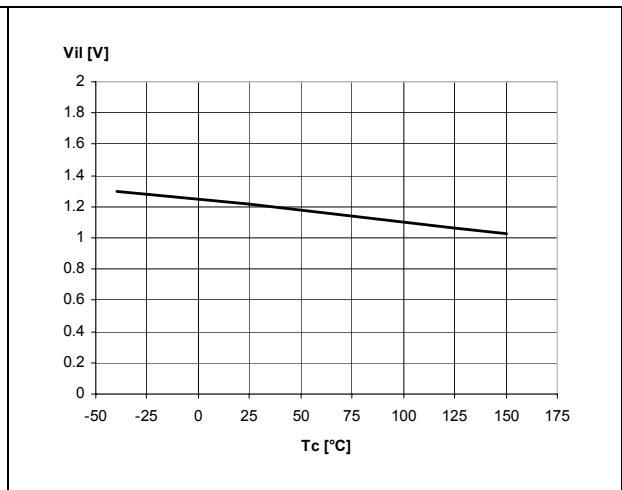


Figure 21. Input high level voltage

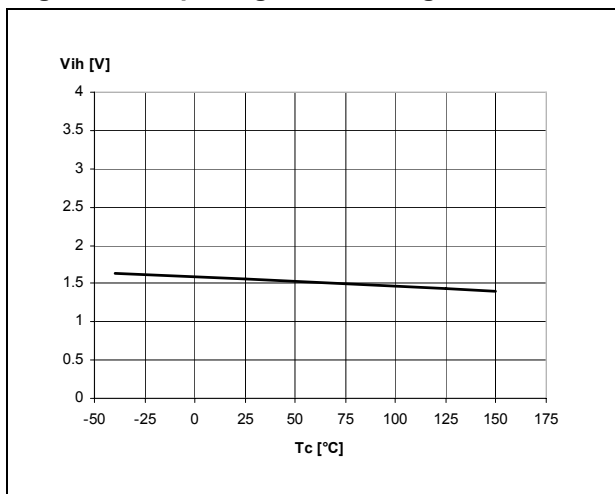


Figure 22. Input hysteresis voltage

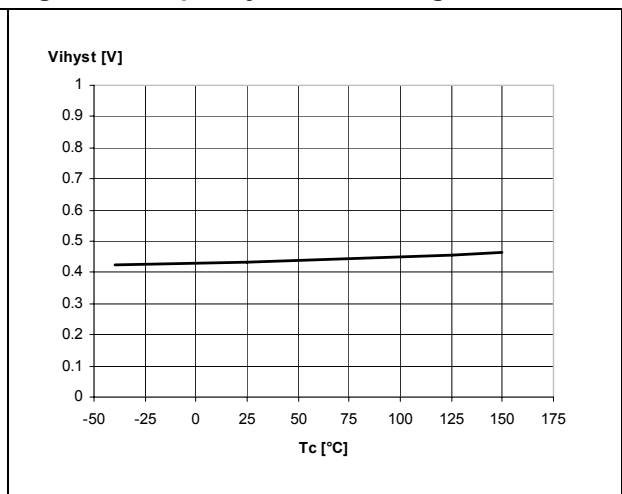


Figure 23. On-state resistance vs  $T_{case}$

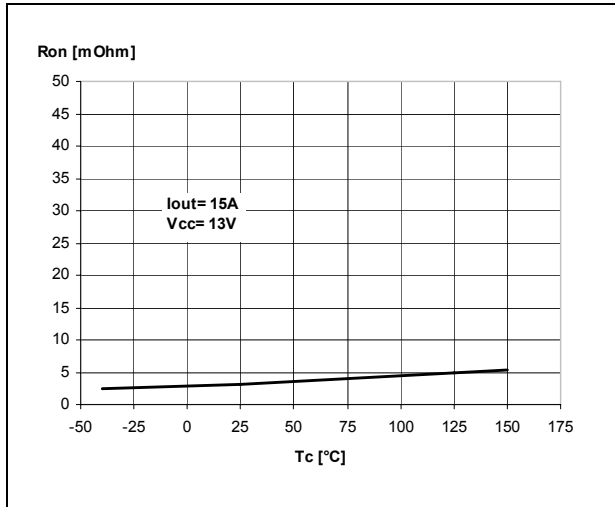


Figure 24. On-state resistance vs  $V_{CC}$

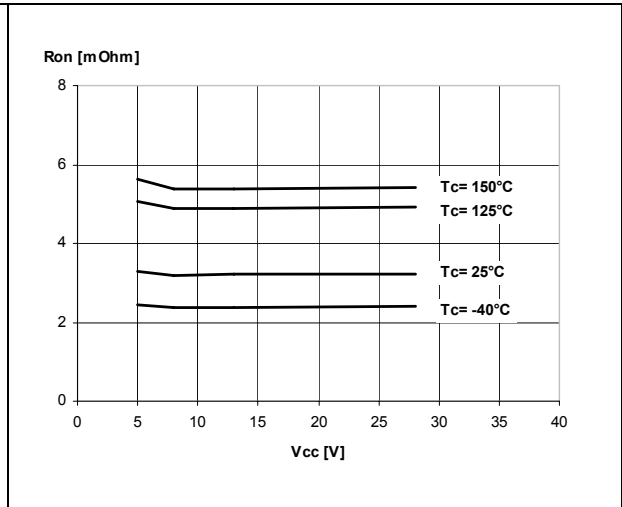


Figure 25. Undervoltage shutdown

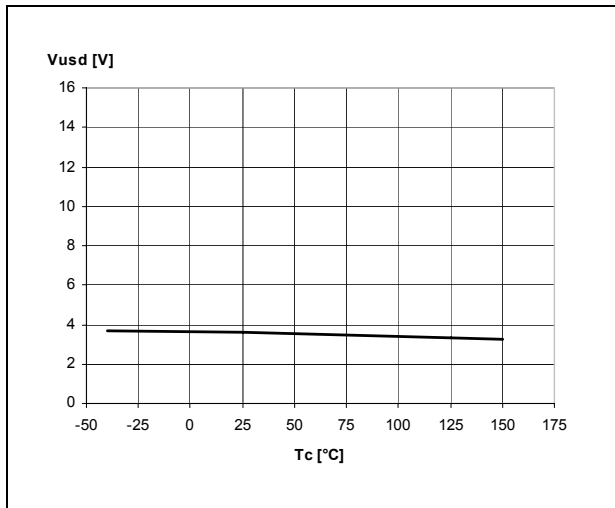


Figure 26. Turn-on voltage slope

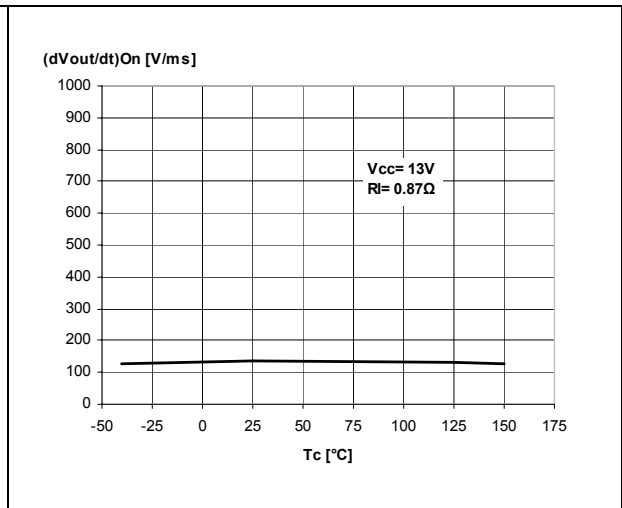


Figure 27.  $I_{LIMH}$  vs  $T_{case}$

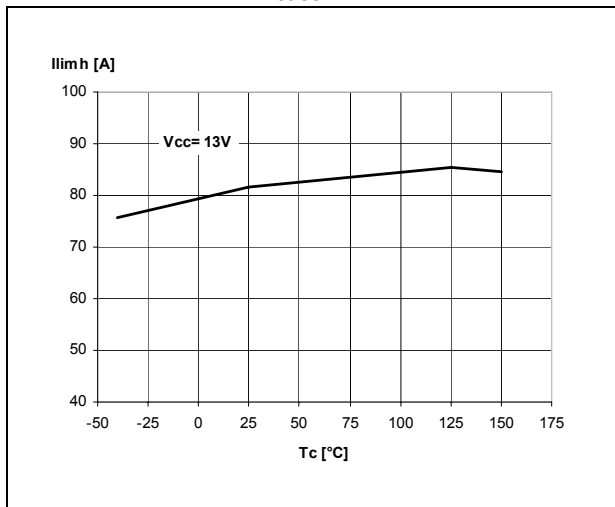


Figure 28. Turn-off voltage slope

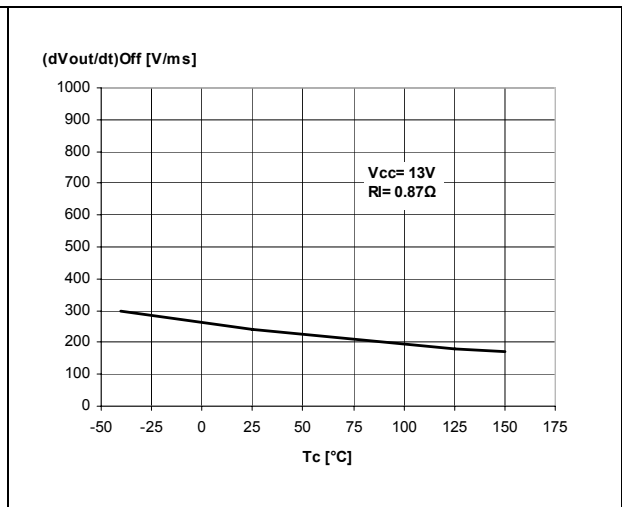


Figure 29. DE high level voltage

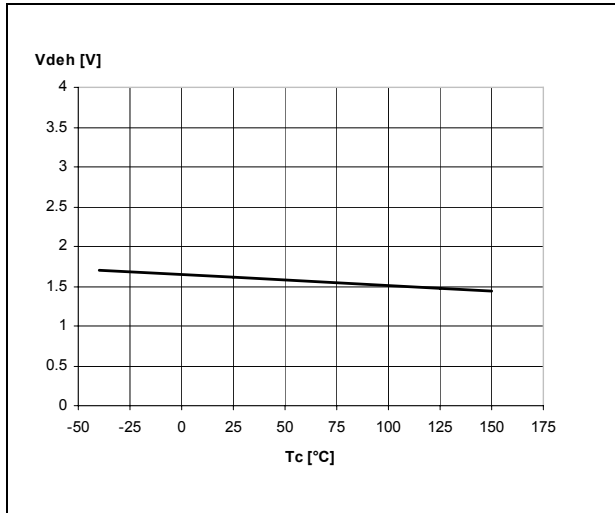


Figure 30. DE clamp voltage

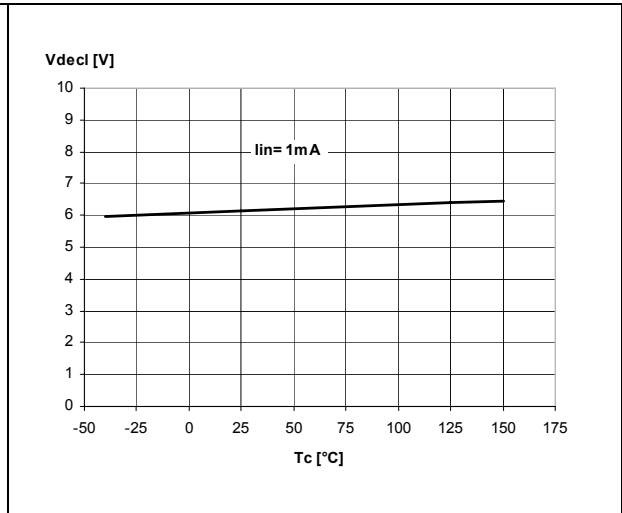
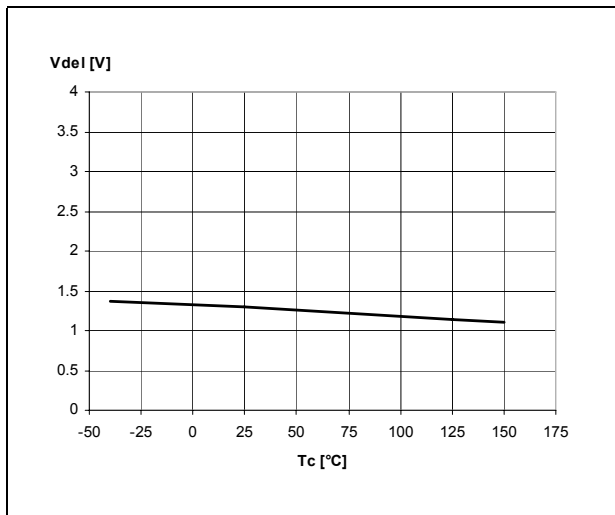
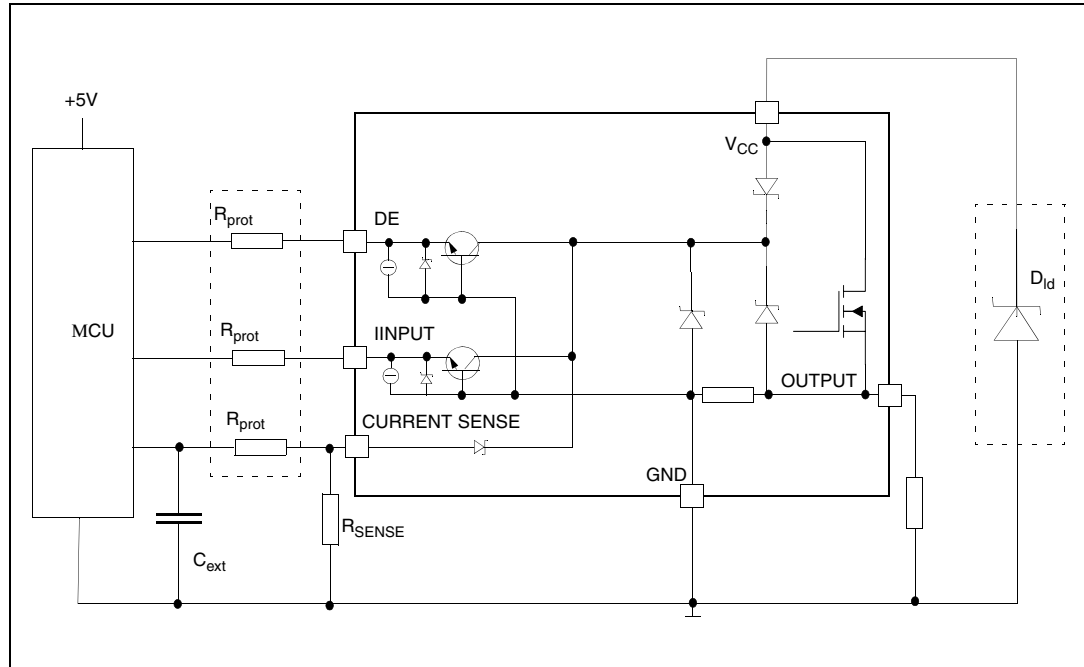


Figure 31. DE low level voltage



### 3 Application information

Figure 32. Application schematic



#### 3.1 MCU I/Os protection

When negative transients are present on the  $V_{CC}$  line, the control pins are pulled negative to approximately  $-1.5V$ .

ST suggests the insertion of resistors ( $R_{prot}$ ) in the lines to prevent the microcontroller I/O pins from latching up.

The values of these resistors provide a compromise between the leakage current of the microcontroller, the current required by the HSD I/Os (input levels compatibility) and the latch-up limit of the microcontroller I/Os.

$$-V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH\mu C} - V_{IH}) / I_{IHmax}$$

Calculation example:

For  $V_{CCpeak} = -1.5V$  and  $I_{latchup} \geq 20mA$ ;  $V_{OH\mu C} \geq 4.5V$

$$75\Omega \leq R_{prot} \leq 240k\Omega$$

Recommended values:  $R_{prot} = 10k\Omega$ ,  $C_{EXT} = 10nF$

#### 3.2 Load dump protection

$D_{ld}$  is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds the  $V_{CCPK}$  maximum rating. The same applies if the device is subject to transients on the  $V_{CC}$  line that are greater than the ones shown in the ISO 7637-2: 2004(E) table.

### 3.3 Current sense and diagnostic

The current sense pin performs a double function (see [Figure 33: Current sense and diagnostics](#)):

- **Current mirror of the load current in normal operation**, delivering a current proportional to the load current according to a known ratio  $K_X$ .  
The current  $I_{SENSE}$  can be easily converted to a voltage  $V_{SENSE}$  by means of an external resistor  $R_{SENSE}$ . Linearity between  $I_{OUT}$  and  $V_{SENSE}$  is ensured up to 5V minimum (see parameter  $V_{SENSE}$  in [Table 9: Current sense \(8 V <  \$V\_{CC}\$  < 18 V\)](#)). The current sense accuracy depends on the output current (refer to current sense electrical characteristics [Table 9: Current sense \(8 V <  \$V\_{CC}\$  < 18 V\)](#)).
- **Diagnostic flag in fault conditions**, delivering a fixed voltage  $V_{SENSEH}$  up to a maximum current  $I_{SENSEH}$  in case of the following fault conditions (refer to [Table 11: Truth table](#)):
  - Power limitation activation
  - Overtemperature
  - Short to  $V_{CC}$  in off-state
  - Open-load in off-state with additional external components.

A logic level low on the DE pin simultaneously sets all the current sense pins of the device in a high impedance state, thus disabling the current monitoring and diagnostic detection. This feature allows multiplexing of the microcontroller analog inputs by sharing the sense resistance and ADC line among different devices.



$R_{PD} \leq 22 \text{ K}\Omega$  is recommended.

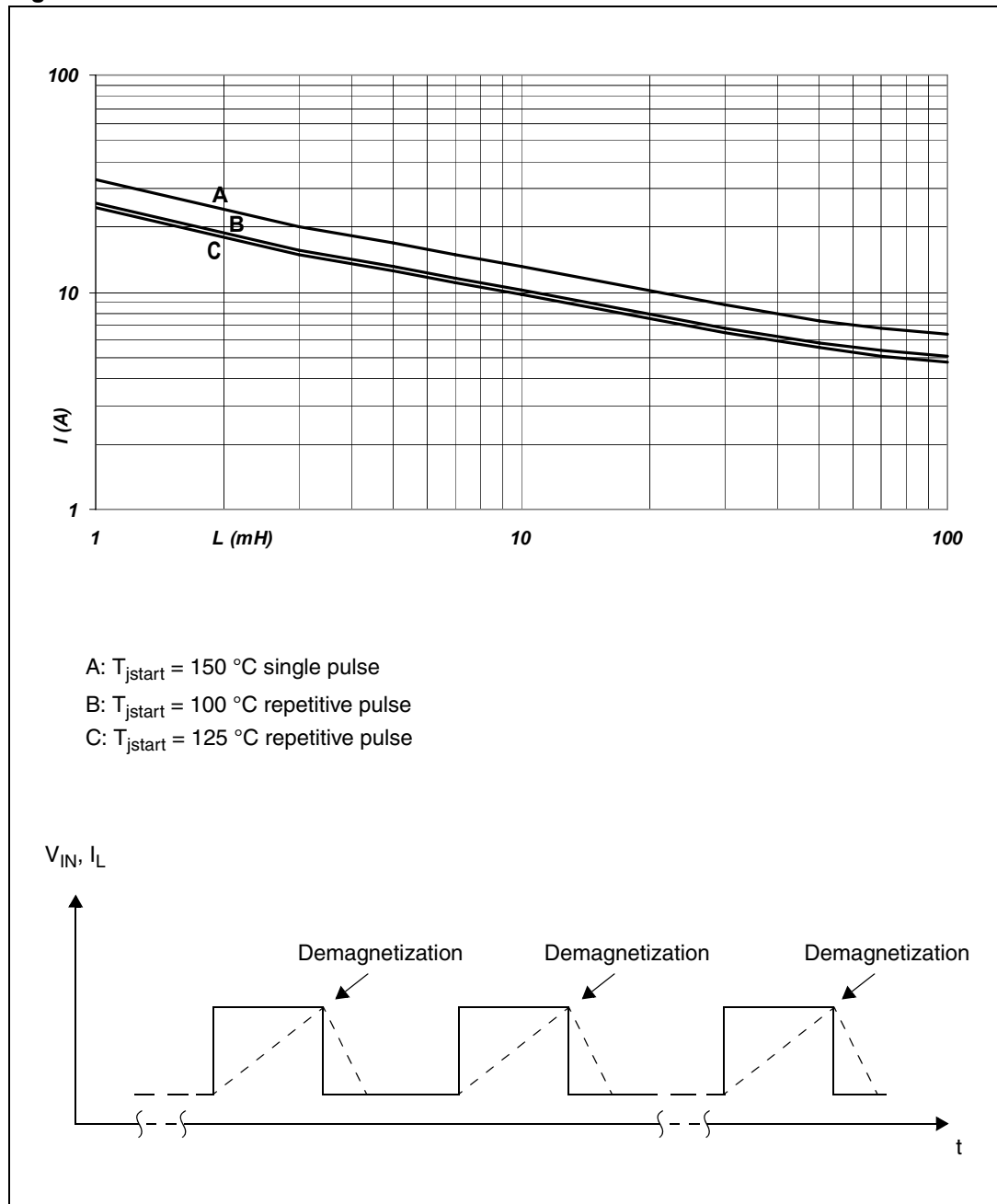
For proper open-load detection in off-state, the external pull-up resistor must be selected according to the following formula:

$$V_{OUT} \Big|_{\text{Pull-up\_ON}} = \frac{R_{PD} \cdot V_{PU} - R_{PU} \cdot R_{PD} \cdot I_{L(\text{off}2)r}}{R_{PU} + R_{PD}} > V_{OL\text{max}} = 4V$$

For the values of  $V_{OL\text{min}}$ ,  $V_{OL\text{max}}$ ,  $I_{L(\text{off}2)r}$  and  $I_{L(\text{off}2)f}$  see [Table 10: Open-load detection](#) ( $8V < V_{CC} < 18V$ ,  $V_{DE} = 5V$ ).

### 3.4 Maximum demagnetization energy ( $V_{CC} = 13.5V$ )

Figure 34. Maximum turn-off current versus inductance <sup>(1)</sup>

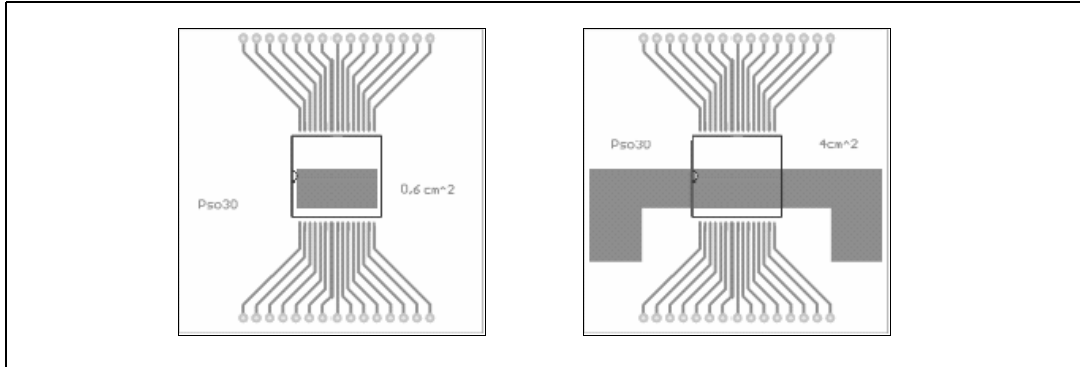


1. Values are generated with  $R_L = 0\text{ }\Omega$ .  
 In case of repetitive pulses,  $T_{jstart}$  (at beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves A and B.

## 4 Package and PC board thermal data

### 4.1 MultiPowerSO-30 thermal data

Figure 35. MultiPowerSO-30 PC board<sup>(1)</sup>



1. Layout condition of  $R_{th}$  and  $Z_{th}$  measurements (PCB: double layer, thermal vias, FR4 area = 58 mm x 58 mm, PCB thickness = 2 mm, Cu thickness = 70  $\mu$ m (front and back side), copper areas: from minimum pad lay-out to 16 cm<sup>2</sup>).

Figure 36.  $R_{thj-amb}$  vs PCB copper area in open box free air condition (one channel ON)

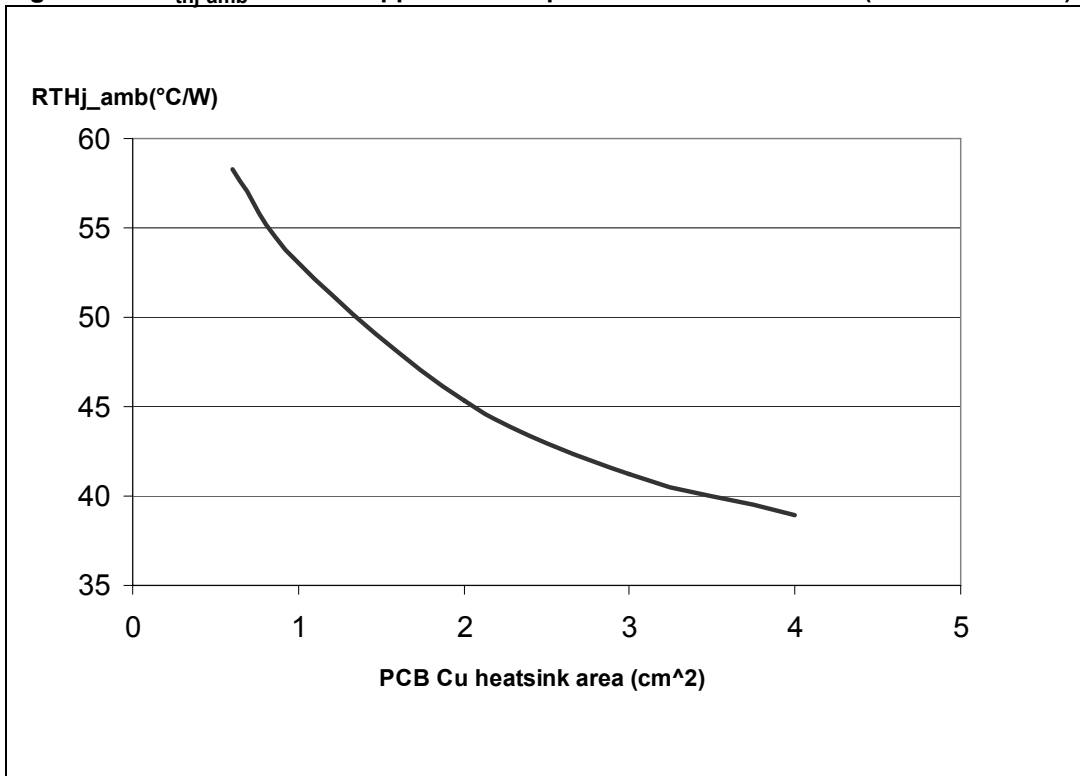


Figure 37. MultiPowerSO-30 thermal impedance junction ambient single pulse (one channel ON)

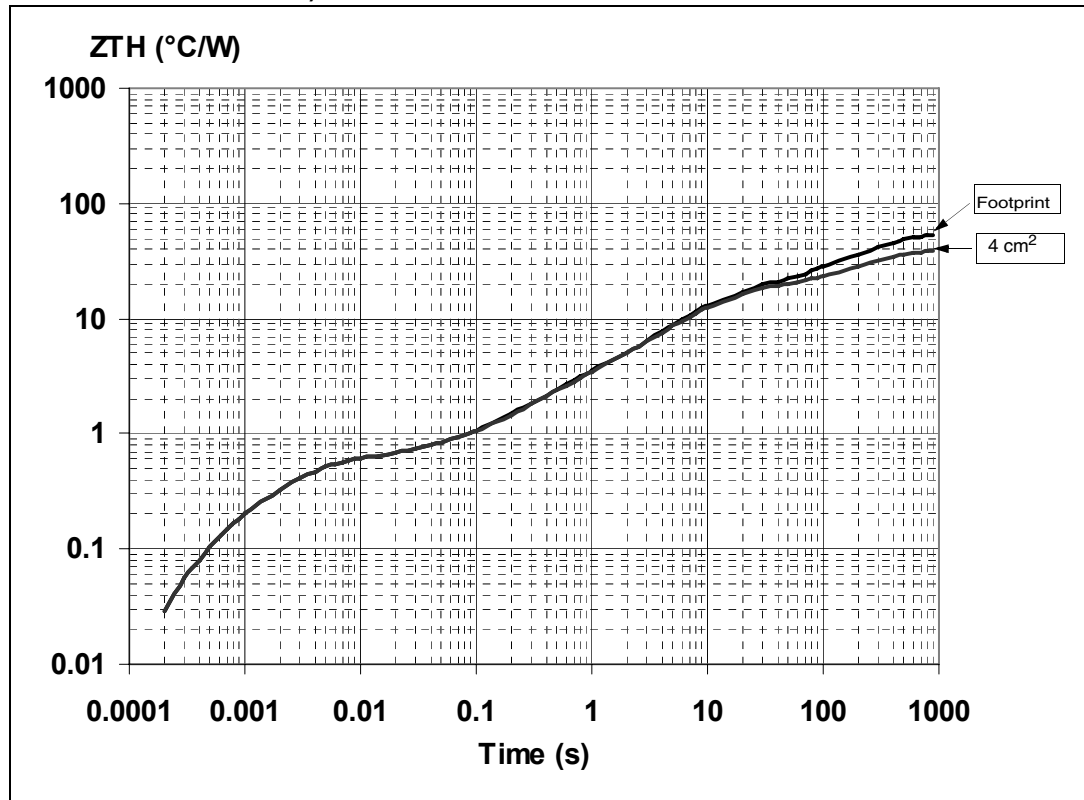
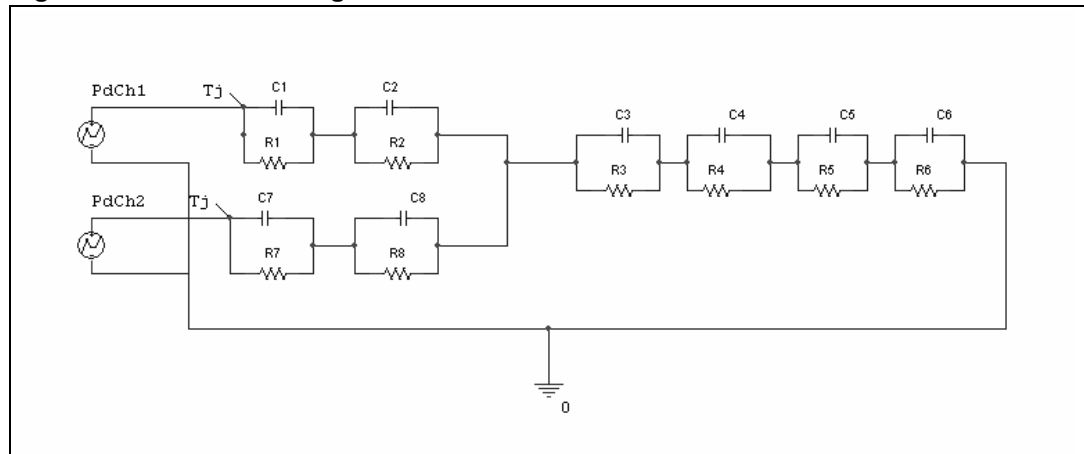


Figure 38. Thermal fitting model of a double channel HSD in MultiPowerSO-30<sup>(1)</sup>



1. The fitting model is a simplified thermal tool and is valid for transient evolutions where the embedded protection functions (power limitation or thermal cycling during thermal shutdown) are not triggered.

**Equation 1: Pulse calculation formula**

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THtp}(1 - \delta)$$

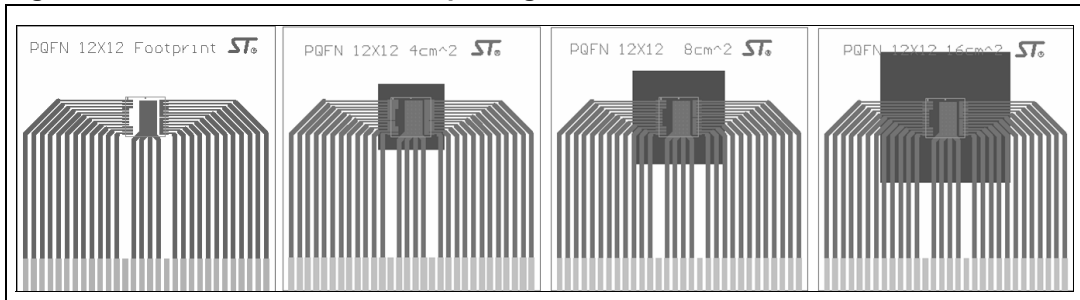
where  $\delta = t_p/T$

**Table 15. Thermal parameters for MultiPowerSO-30**

Area/island (cm <sup>2</sup> )	Footprint	4
R1 (°C/W)	0.05	
R2 (°C/W)	0.3	
R3 (°C/W)	0.5	
R4 (°C/W)	1.3	
R5 (°C/W)	14	
R6 (°C/W)	44.7	23.7
R7 (°C/W)	0.05	
R8 (°C/W)	0.3	
C1 (W.s/°C)	0.005	
C2 (W.s/°C)	0.008	
C3 (W.s/°C)	0.01	
C4 (W.s/°C)	0.3	
C5 (W.s/°C)	0.6	
C6 (W.s/°C)	5	11
C7 (W.s/°C)	0.005	
C8 (W.s/°C)	0.008	

## 4.2 PQFN - 12x12 power lead-less thermal data

Figure 39. 12x12 Power lead-less package PC board<sup>(1)</sup>



1. Layout condition of  $R_{th}$  and  $Z_{th}$  measurements (PCB: double layer, thermal vias, FR4 area = 77 mm x 86 mm, PCB thickness = 1.6 mm, Cu thickness = 70  $\mu$ m (front and back side), copper areas: minimum pad lay-out).

Figure 40.  $R_{thj-amb}$  vs PCB copper area in open box free air condition (one channel ON)

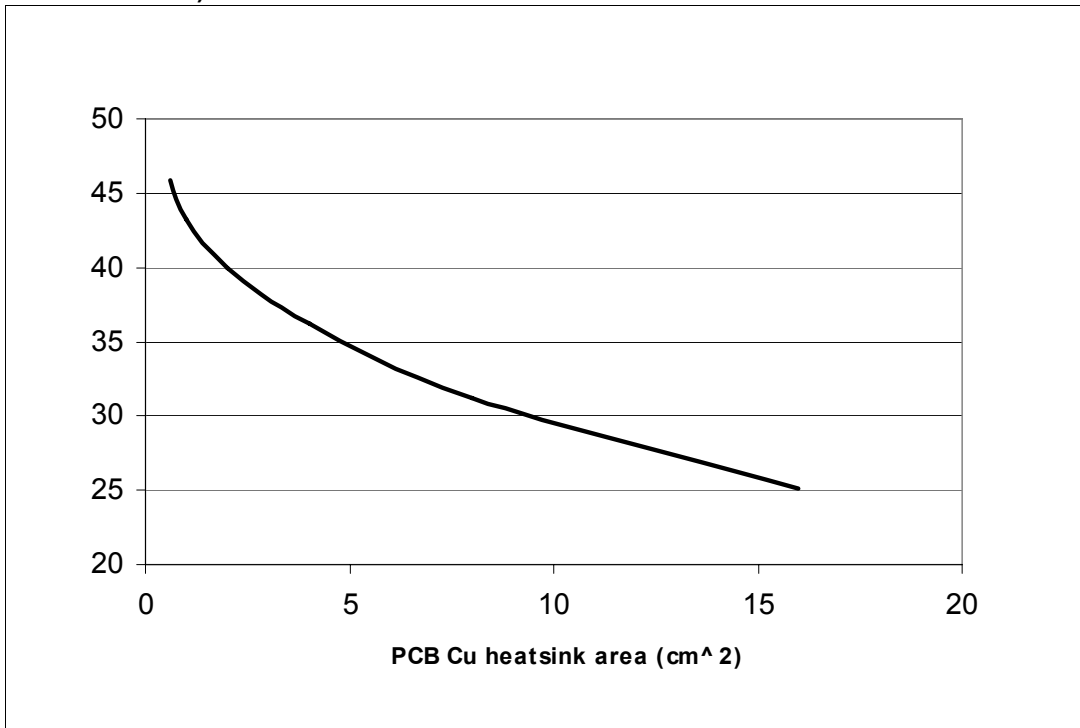


Figure 41. PQFN - 12x12 power lead-less package thermal impedance junction ambient single pulse (one channel ON)

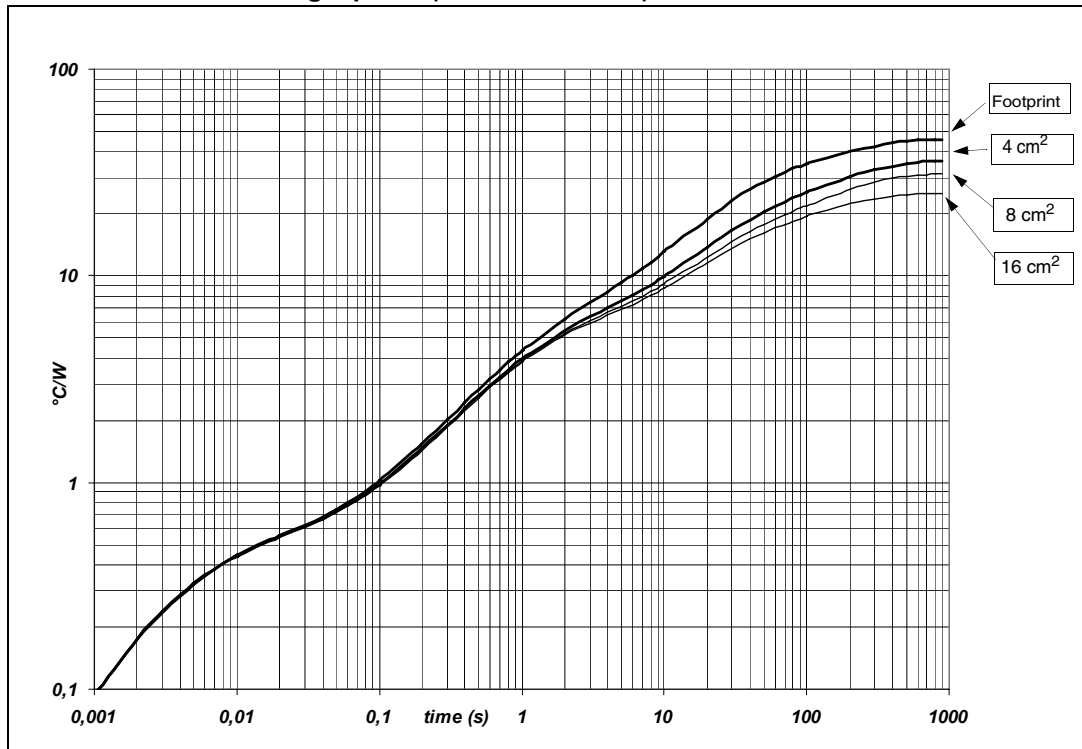
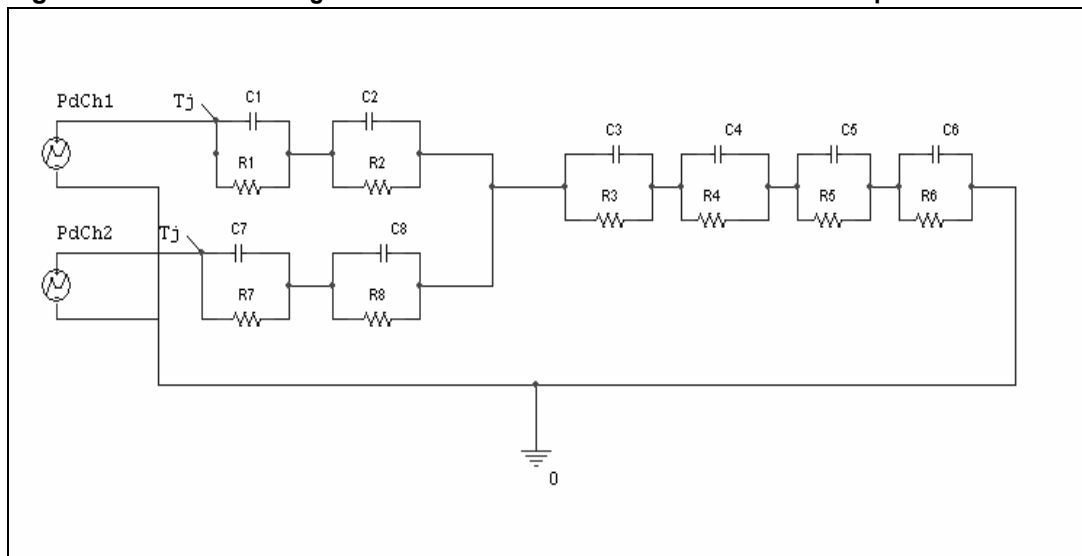


Figure 42. Thermal fitting model of a double channel HSD in PQFN - 12x12 power lead-less<sup>(1)</sup>



1. The fitting model is a simplified thermal tool and is valid for transient evolutions where the embedded protection functions (power limitation or thermal cycling during thermal shutdown) are not triggered.

**Equation 2: pulse calculation formula**

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THtp}(1 - \delta)$$

where  $\delta = t_p/T$

**Table 16. Thermal parameters for PQFN - 12x12 power lead-less**

Area/island (cm <sup>2</sup> )	Footprint	4	8	16
R1 (°C/W)	0.35			
R2 (°C/W)	0.15			
R3 (°C/W)	4.2			
R4 (°C/W)	9.6	9.4	9.2	9
R5 (°C/W)	15.1	10.5	8.5	5.5
R6 (°C/W)	16.7	12	9	6
R7 (°C/W)	0.35			
R8 (°C/W)	0.15			
C1 (W.s/°C)	0.018			
C2 (W.s/°C)	0.015			
C3 (W.s/°C)	0.2			
C4 (W.s/°C)	1.9	2.2	2.32	2.45
C5 (W.s/°C)	2.45	7.3	13.7	20
C6 (W.s/°C)	11.85	22	25	30
C7 (W.s/°C)	0.018			
C8 (W.s/°C)	0.015			

## 5 Package and packing information

### 5.1 ECOPACK® packages

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).

ECOPACK® is an ST trademark.

### 5.2 MultiPowerSO-30 mechanical data

Figure 43. MultiPowerSO-30 outline

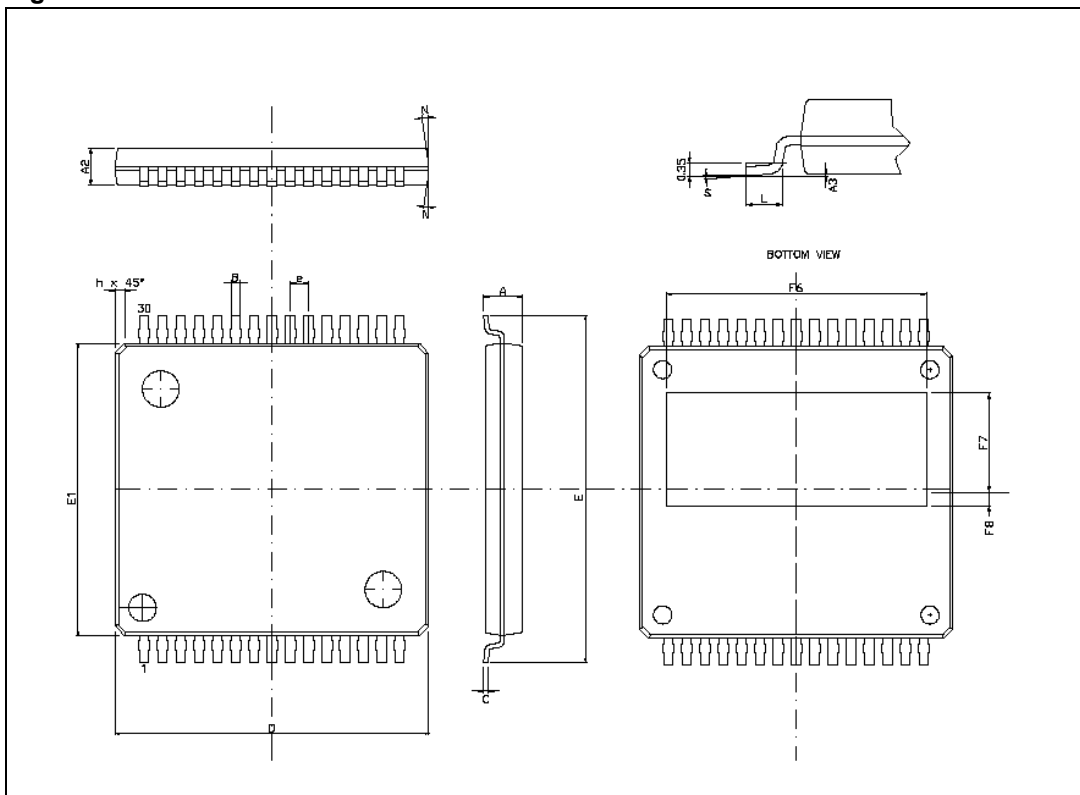


Table 17. MultiPowerSO-30 mechanical data

Symbol	Millimeters		
	Min.	Typ.	Max.
A			2.35
A2	1.85		2.25
A3	0		0.1
B	0.42		0.58
C	0.23		0.32
D	17.1	17.2	17.3
E	18.85		19.15
E1	15.9	16	16.1
"e"	1		
F6		14.3	
F7		5.45	
F8		0.73	
L	0.8		1.15
N			10 Deg
S	0 Deg		7 Deg

### 5.3 PQFN - 12x12 power lead-less mechanical data

Figure 44. PQFN - 12x12 power lead-less outline

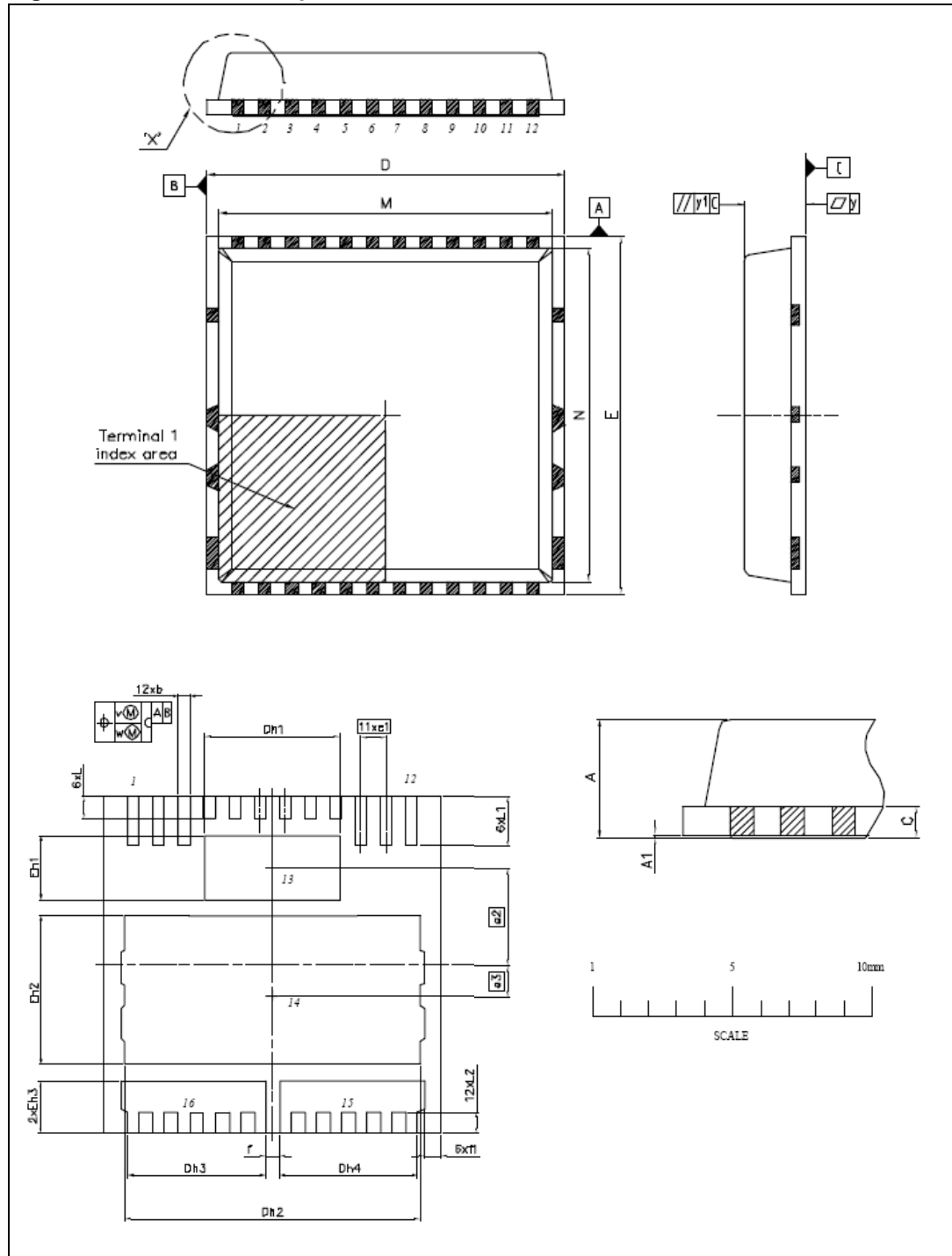


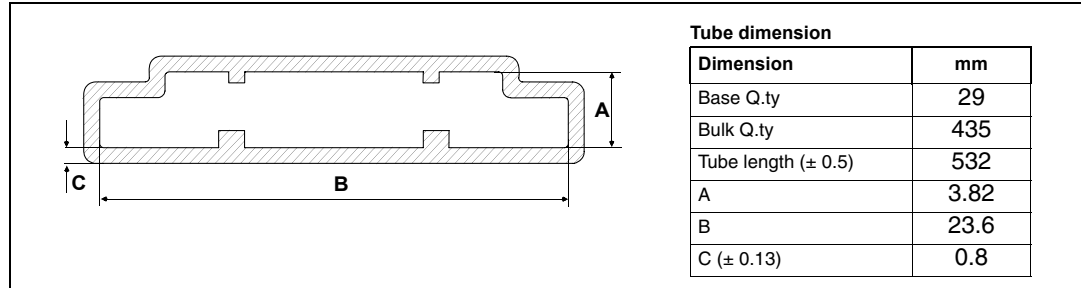
Table 18. PQFN - 12x12 power lead-less mechanical data

Symbol	Millimeters		
	Min.	Typ.	Max.
A	2		2.2
A1	0		0.05
b	0.35		0.47
C		0.50	
D	11.90		12.10
Dh1	4.65		4.95
Dh2	10.45		10.65
Dh3	4.80		5
Dh4	4.80		5
E	11.90		12.10
Eh1	2.15		2.45
Eh2	5.15		5.45
Eh3	1.70		2
e1		0.90	
e2		3.45	
e3		1.10	
f		0.50	
f1		0.60	
L	0.75		0.95
L1	1.65		1.90
L2	0.76		0.78
M	11.10		11.30
N	11.10		11.30
v		0.1	
w		0.05	
y		0.05	
y1		0.1	

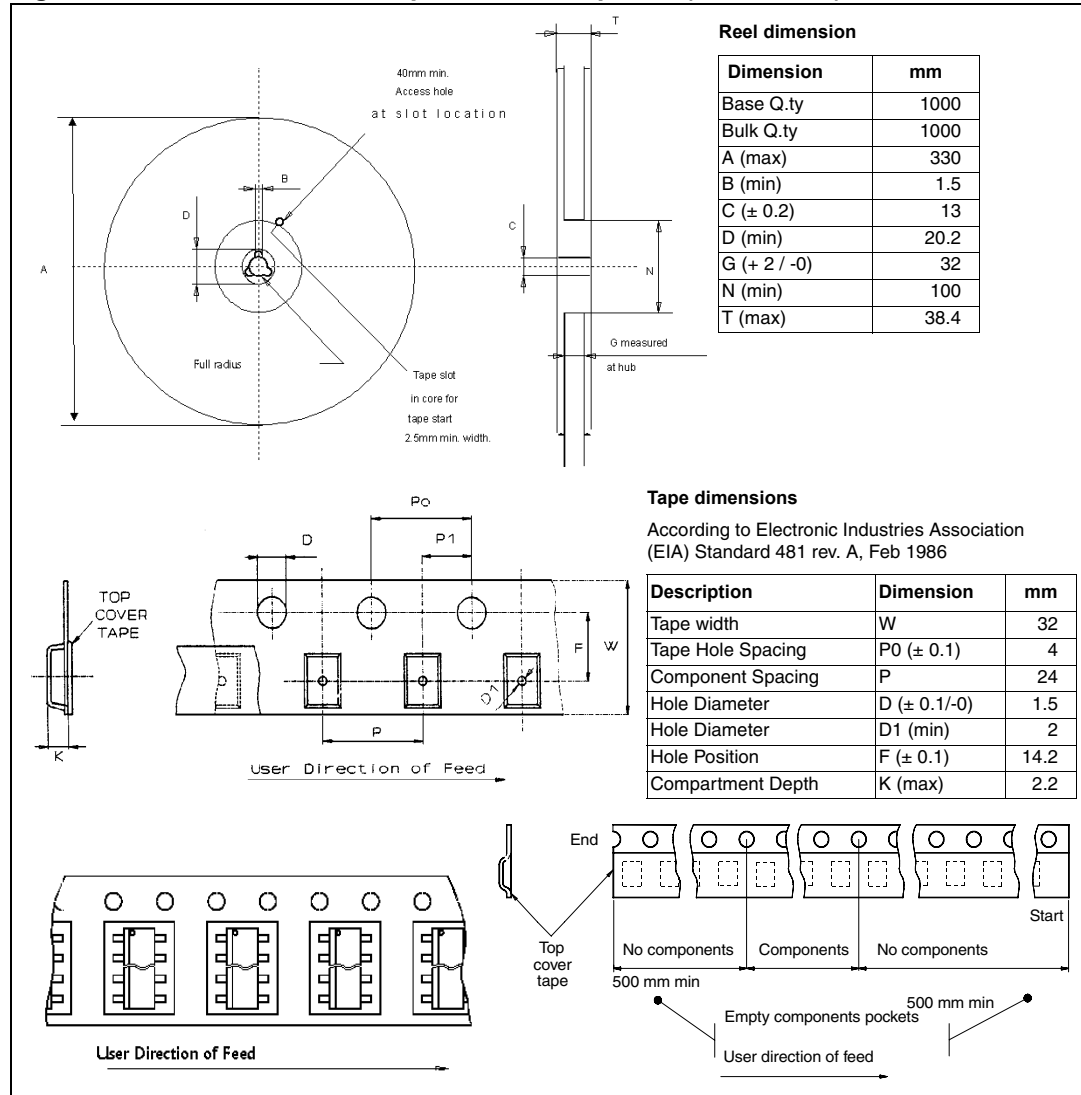
### 5.4 MultiPowerSO-30 packing information

The devices can be packed in tube or tape and reel shipments (see [Table 19: Device summary](#)).

**Figure 45. MultiPowerSO-30 tube shipment (no suffix)**



**Figure 46. MultiPowerSO-30 tape and reel shipment (suffix “TR”)**



### 5.5 PQFN - 12x12 power lead-less packing information

The devices can be packed in tray or tape and reel shipments (see [Table 19: Device summary](#)).

**Figure 47. PQFN - 12x12 power lead-less tray shipment (no suffix)**

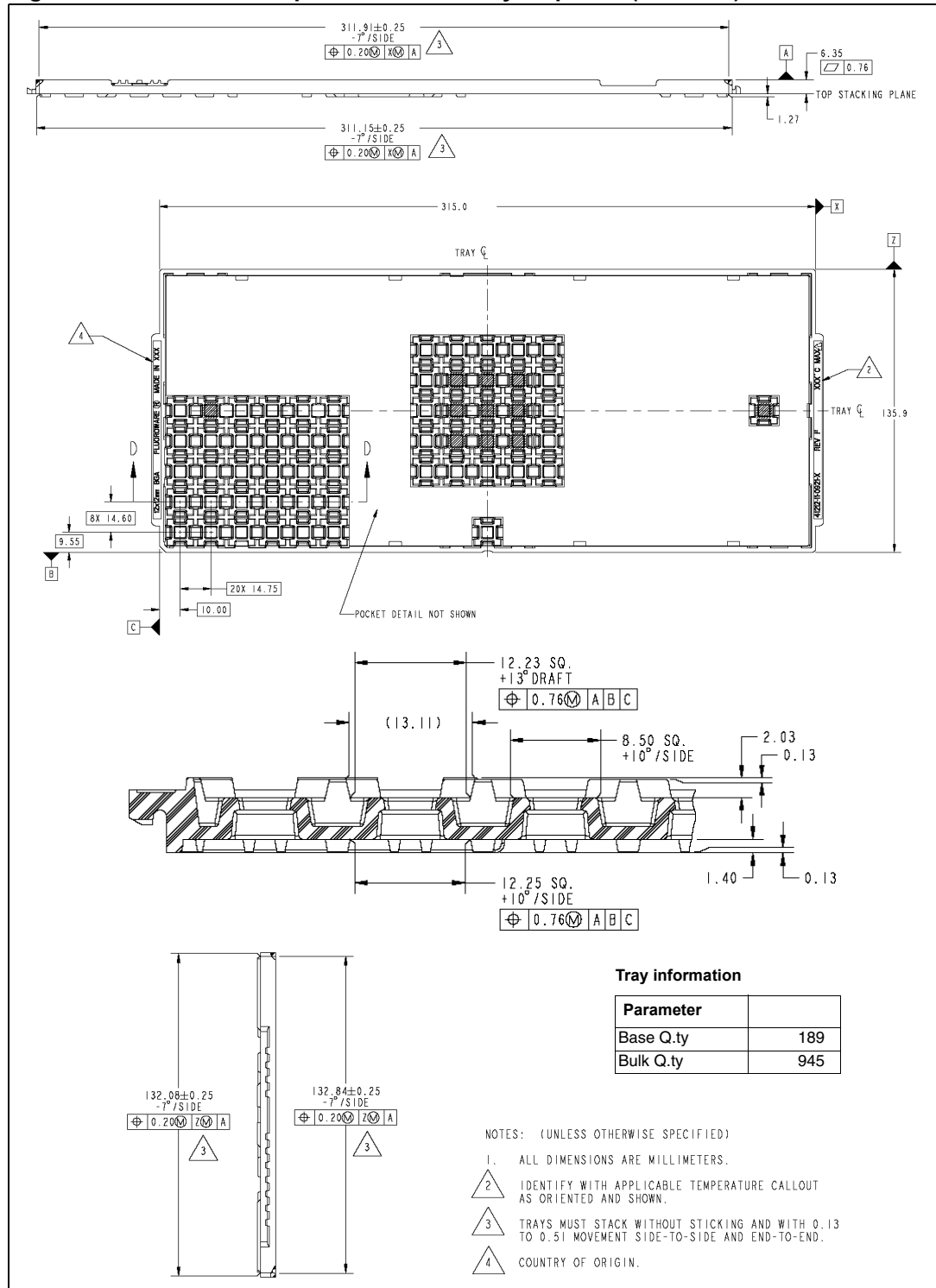
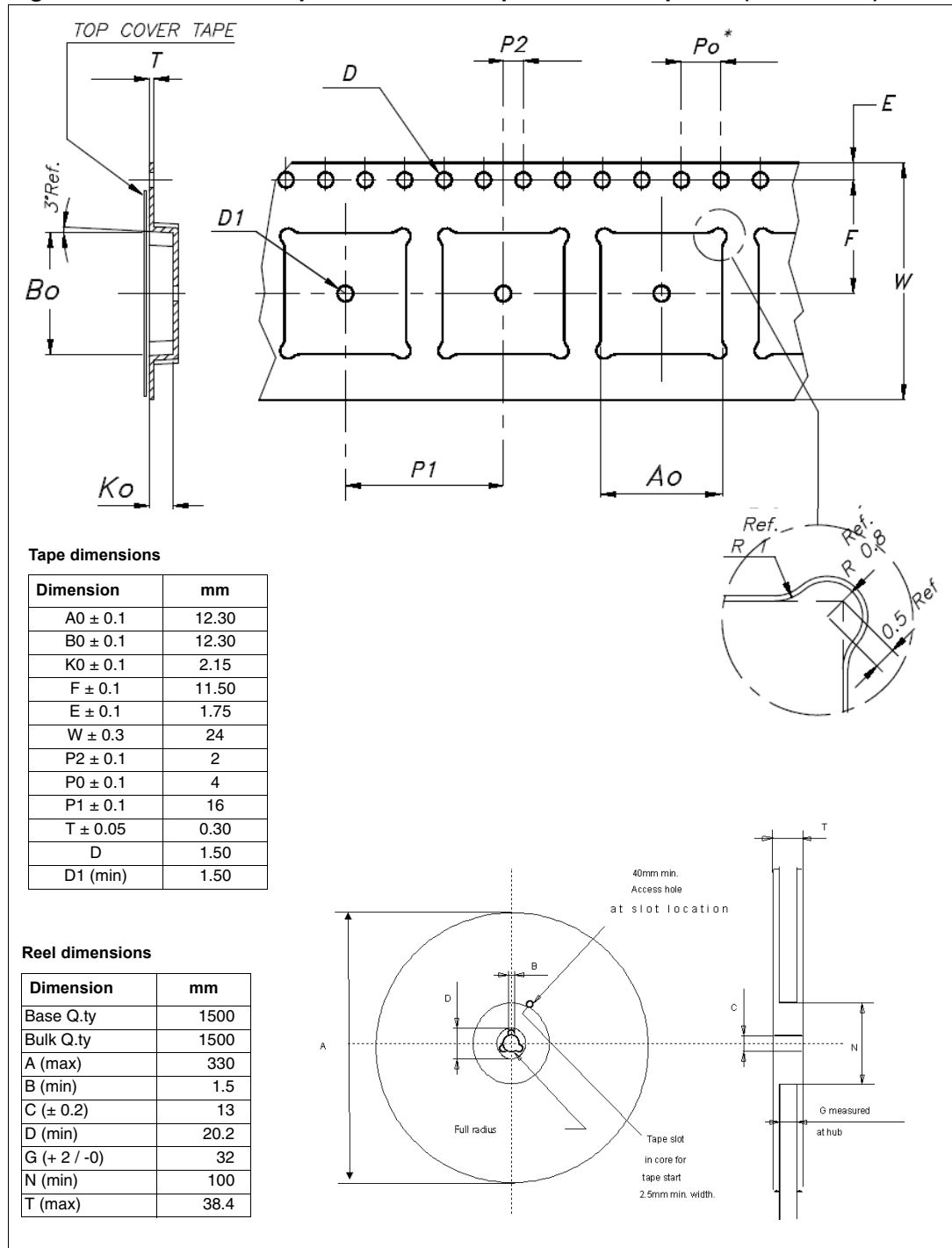


Figure 48. PQFN - 12x12 power lead-less tape and reel shipment (suffix "TR")



## 6 Order codes

Table 19. Device summary

Package	Order codes		
	Tube	Tape and reel	Tray
PQFN-12x12 power lead-less	—	VND5E004ATR-E	VND5E004A-E
MultiPowerSO-30	VND5E004A30-E	VND5E004A30TR-E	—

## 7 Revision history

Table 20. Document revision history

Date	Revision	Changes
20-Jul-2010	1	Initial release.

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